

UMat: Uncertainty-Aware Single Image High Resolution Material Capture

CVPR 2023
Paper ID 7763
TUE-PM-156

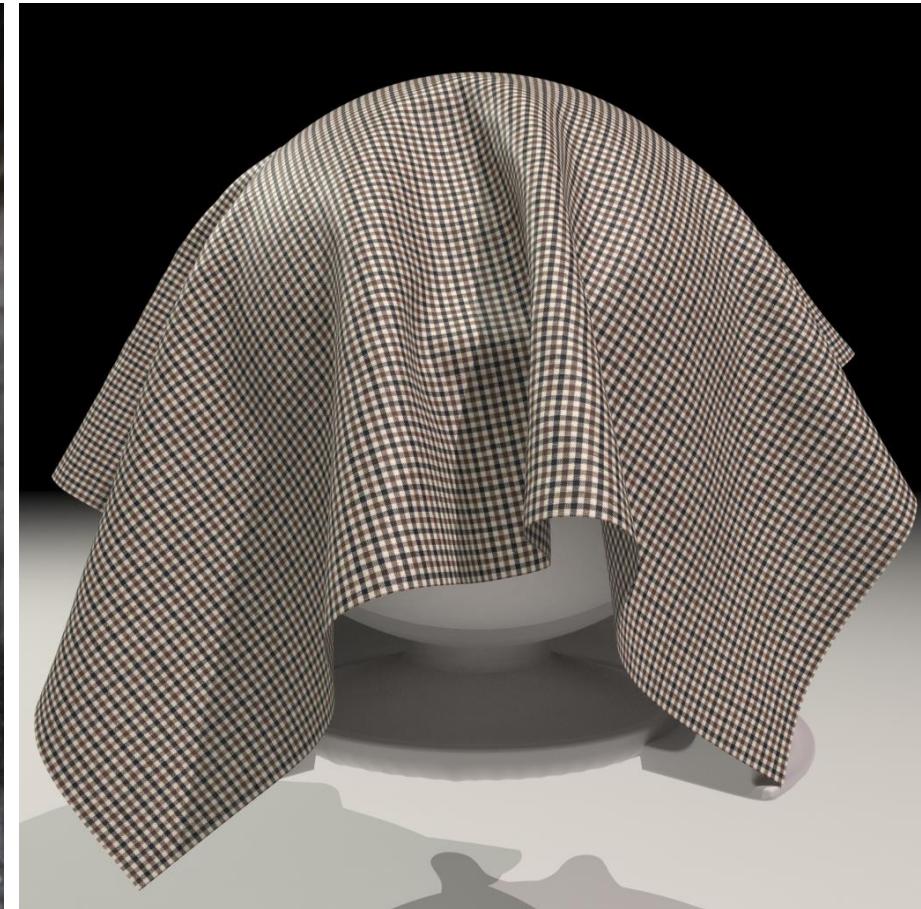
SEDDI



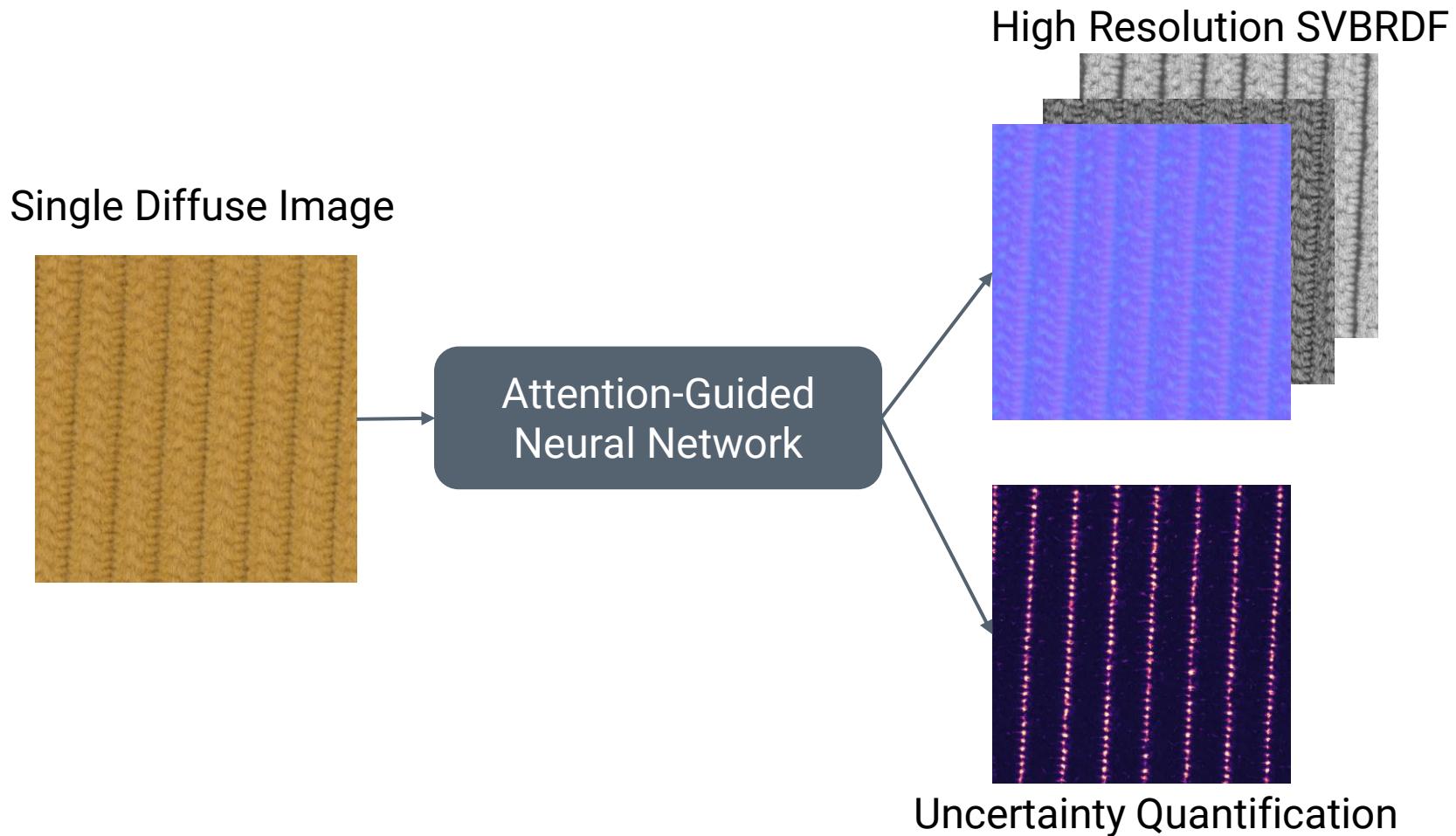
Universidad
Rey Juan Carlos

1-Minute Summary

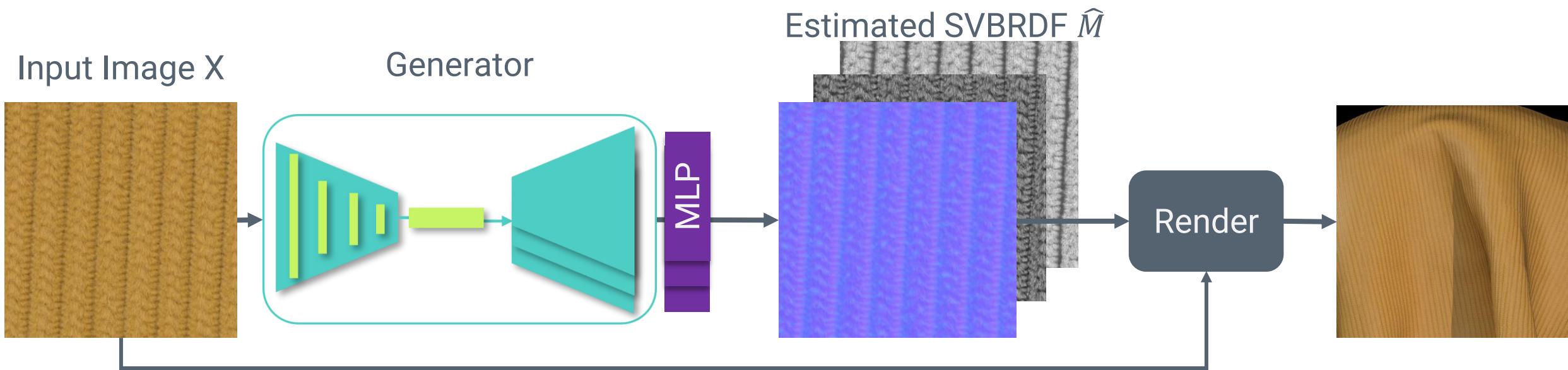
Introduction



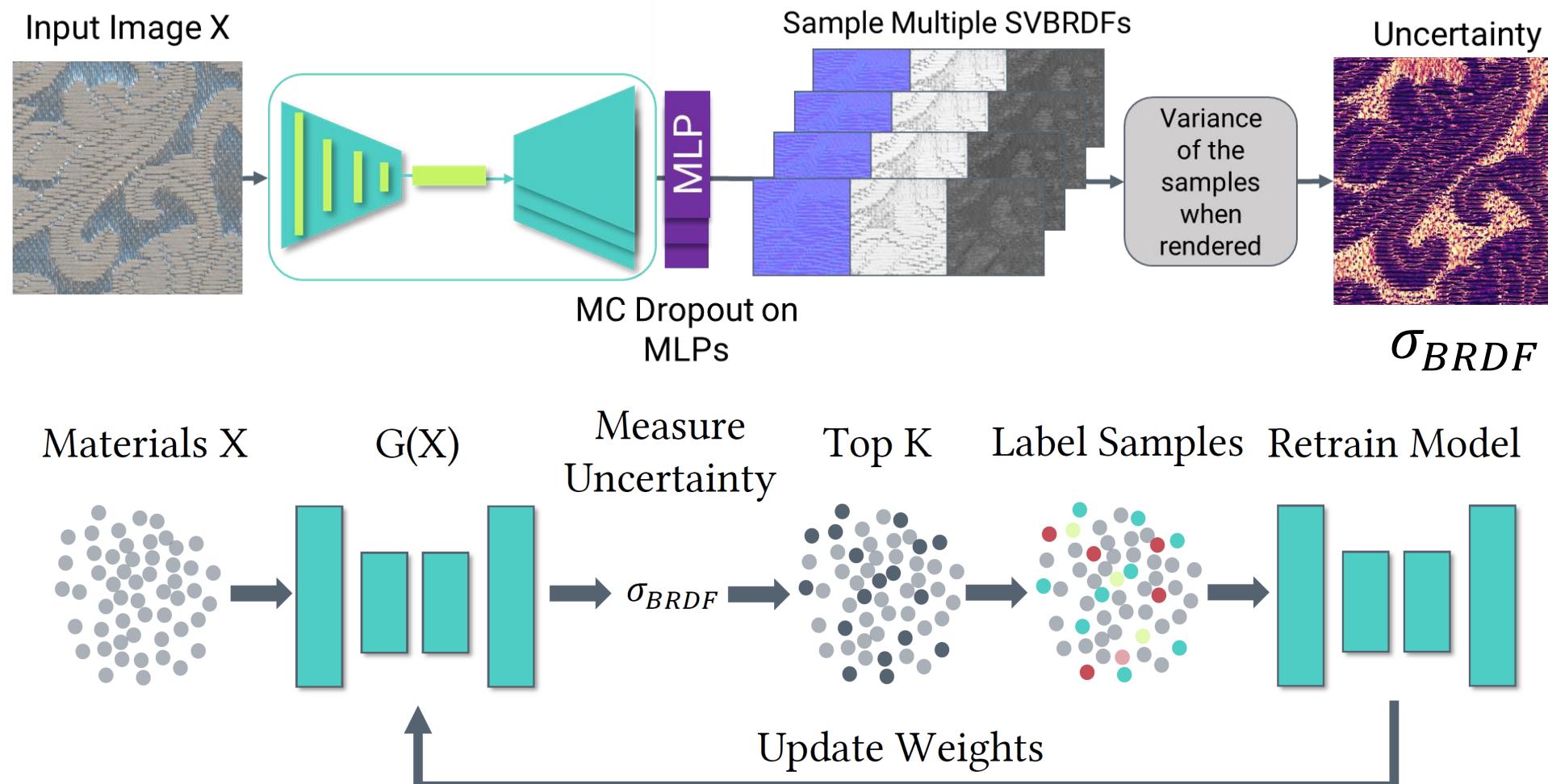
UMat



Inference



Uncertainty Quantification and Active Learning



UMat: Uncertainty-Aware Single Image High Resolution Material Capture

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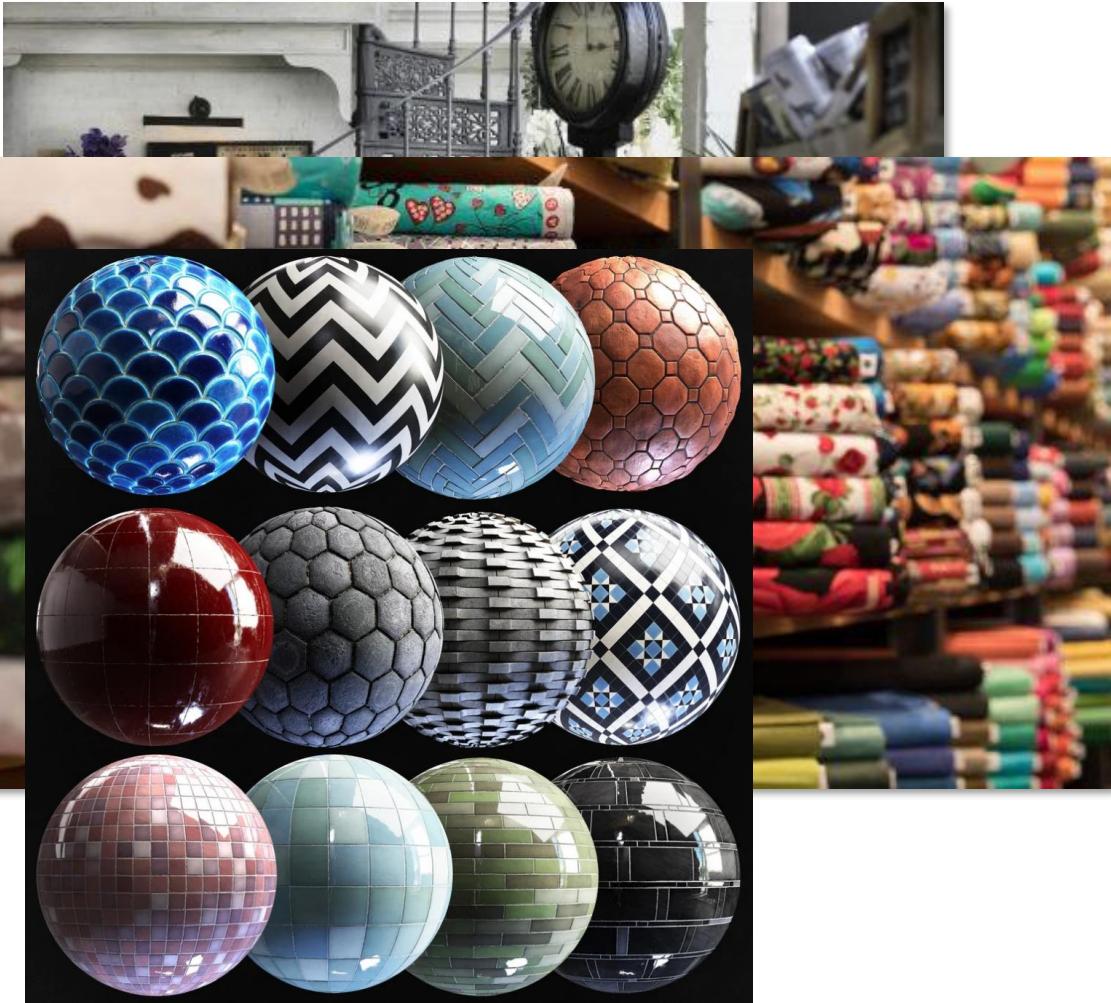
SEDDI



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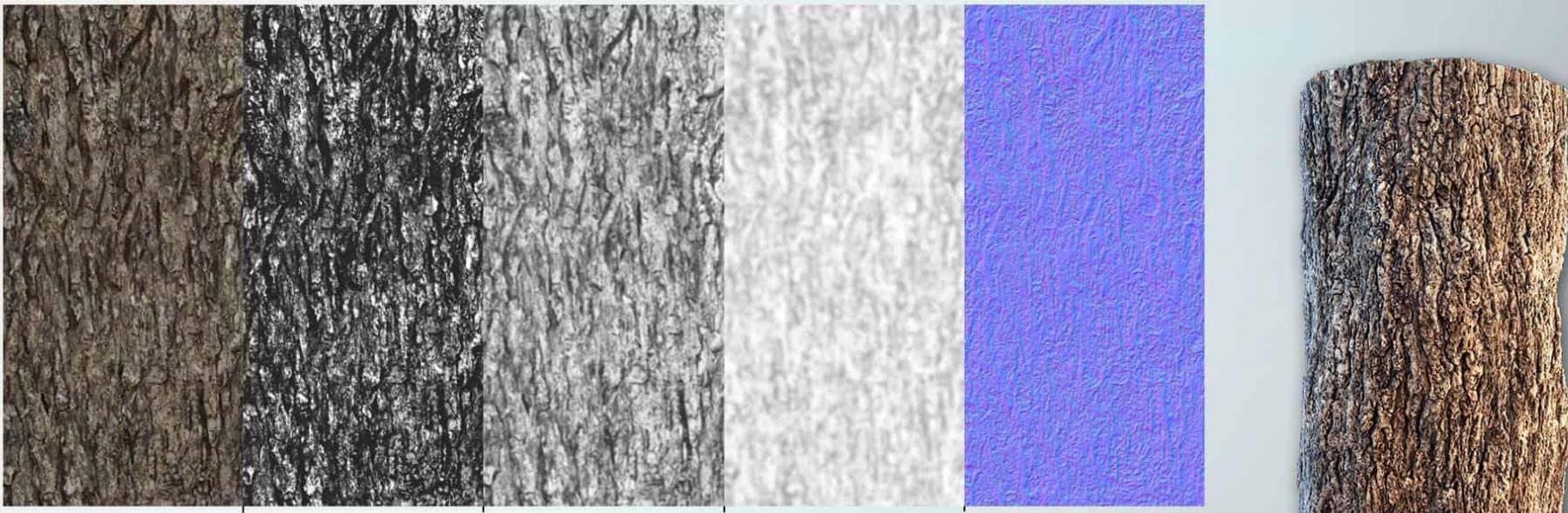
Introduction

Real World Materials



SVBRDFs

BASIC GUIDE FOR TEXTURE MAP TYPES BY YANKO STEFANOV



DIFFUSE

A diffuse map contains the color information of the texture. It defines what original color the texture will have at a certain position.

SPECULAR

A specularity map defines how strong the textured surface will 'shine' at a certain position. Most render engines use this information to define the appearance of specular highlights.

DISPLACEMENT

Displacement maps are similar to bump but store height information and generates 'real' depth by adding geometry when rendered.

AMBIENT OCCLUSION

Ambient occlusion is a method to approximate how bright light should be shining on any specific part of a surface. Place it on top of the Diffuse in "Multiplay mode" in Photoshop

NORMAL

The red, green, and blue channels of the image are used to control the direction of each pixel's normal. Normal map simulates the direction the normal is facing as well as the height, giving a more realistic effect.



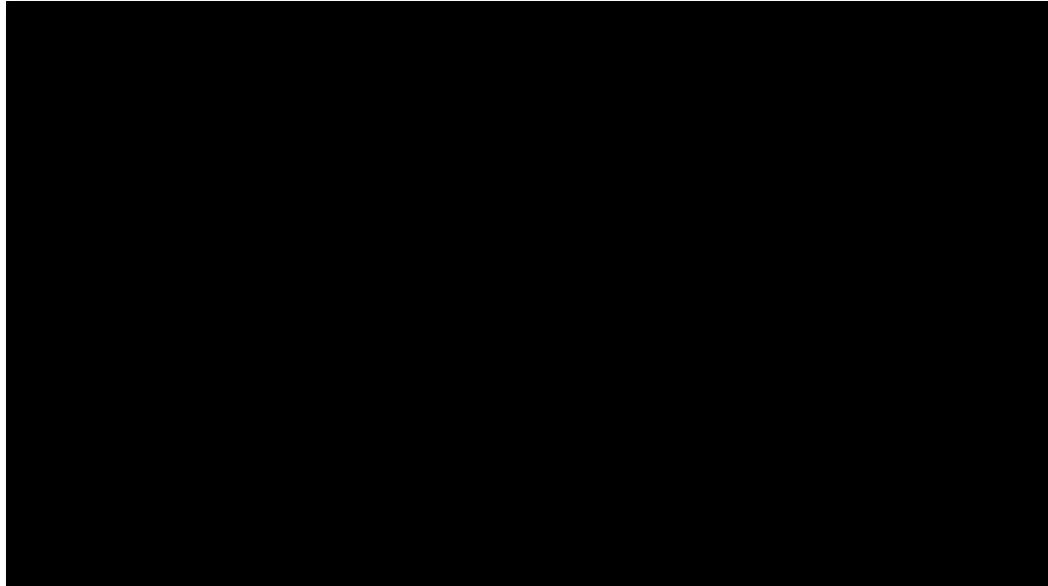
Original model by:
Zeljko Mihajlovic - 3D Artist

Material Capture

Commodity Hardware



Custom Devices (Gonio Reflectometers, TAC7)

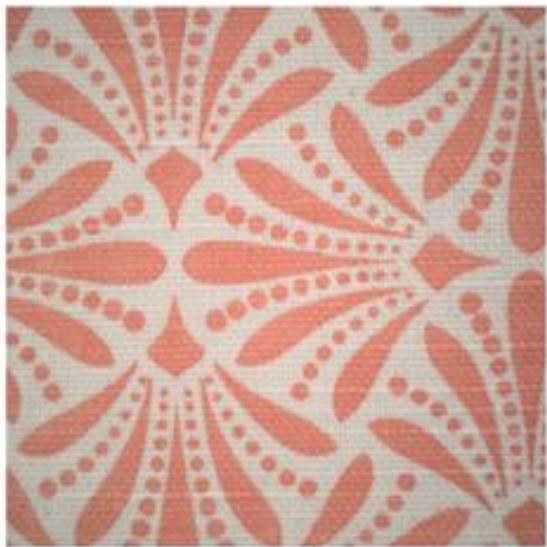


Scalability, Speed

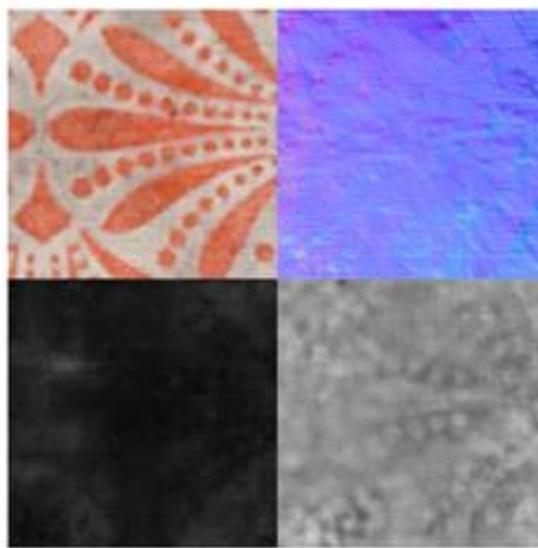
Cost, Quality

Material Capture

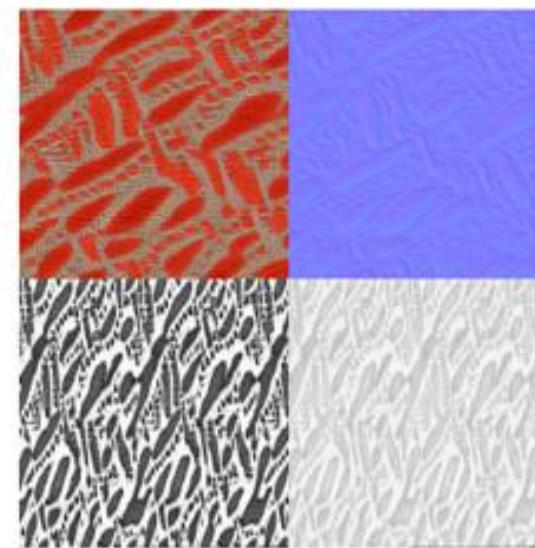
Smartphone Image



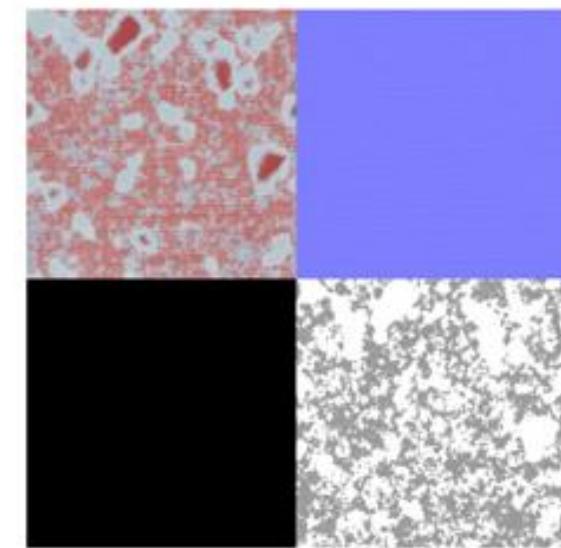
Gao et al.
2019



Henzler et al.
2021



Shi et al.
2020



UMat

GAN tailored for material digitization

High Resolution SVBRDF (up to 1000 ppi)

Flatbed Scanners as Capture Device

Accurate, artifact-free, sharp maps

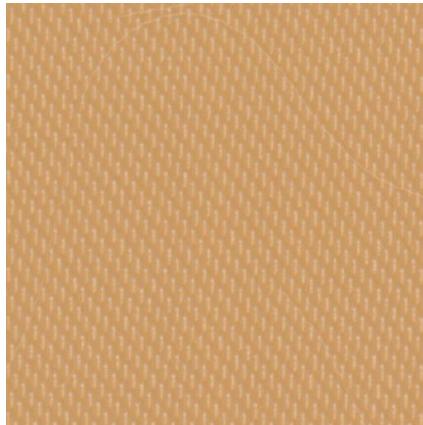
Uncertainty Quantification



Uncertainty in Single Image Material Estimation

How will this look like?

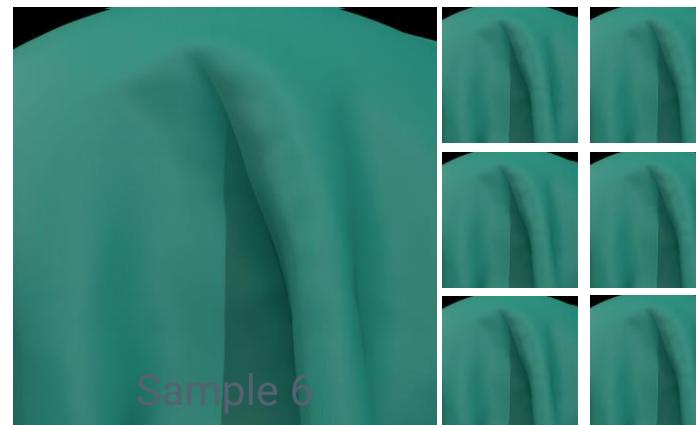
Single
Image
Input



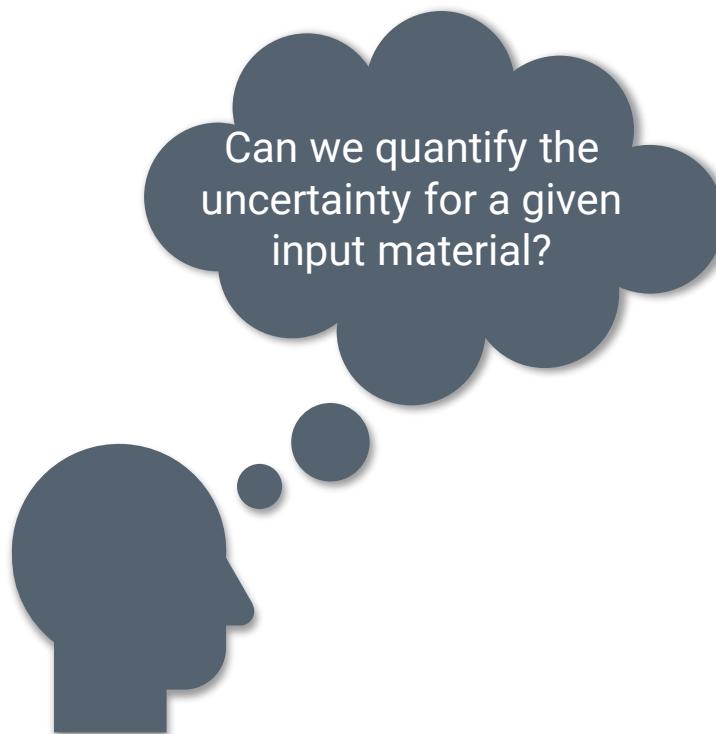
Plausible Model Estimations



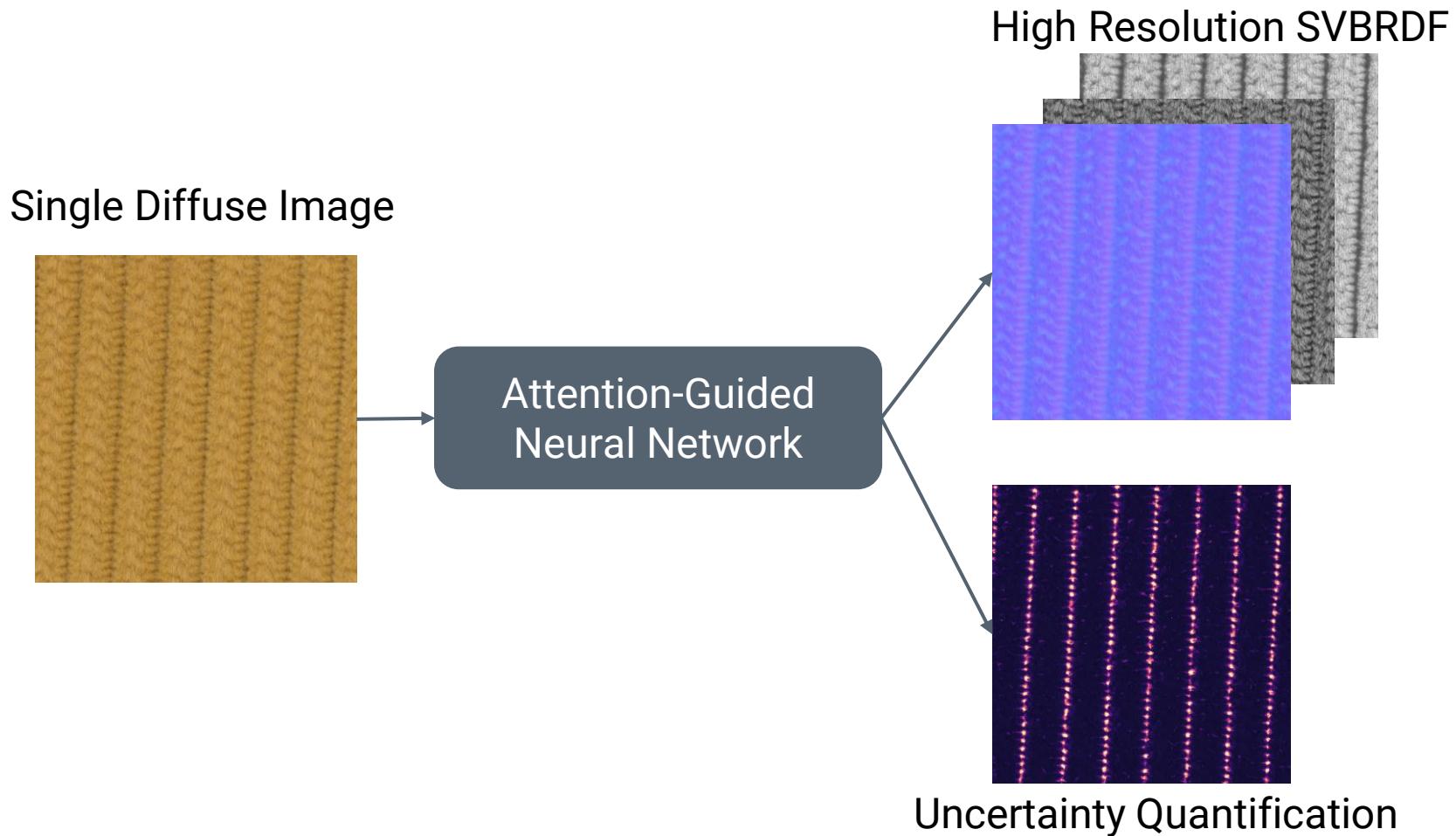
High
Uncertainty



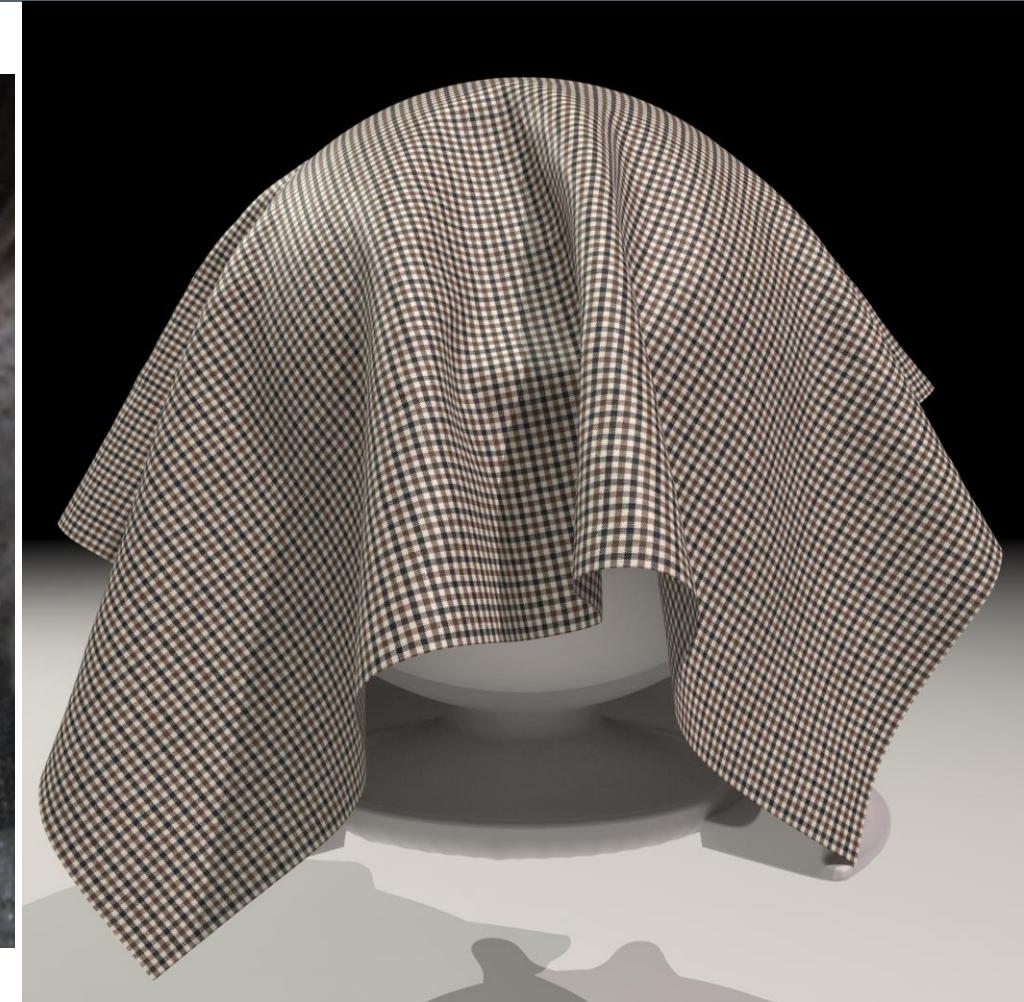
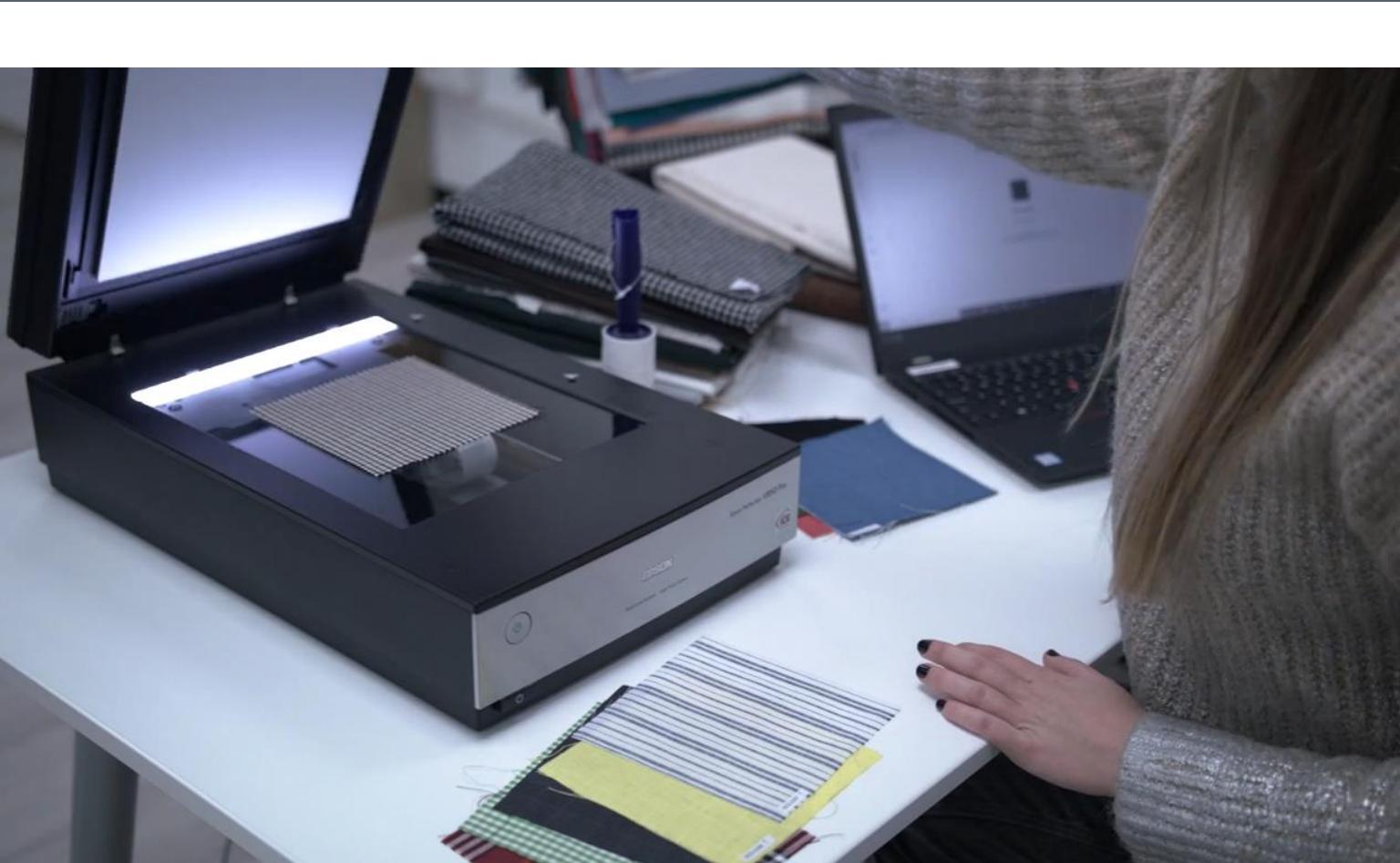
Low
Uncertainty



UMat



Flatbed Scanners



Flatbed Scanners

Scan



Albedo



Scan



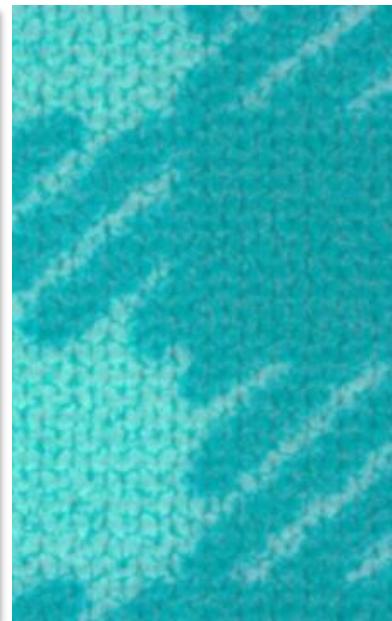
Albedo



Scan

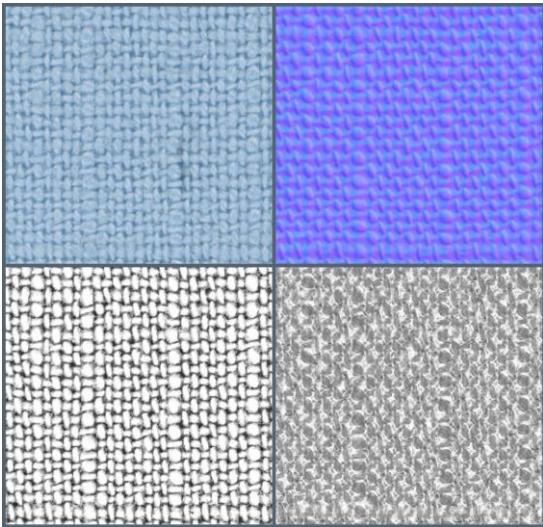


Albedo

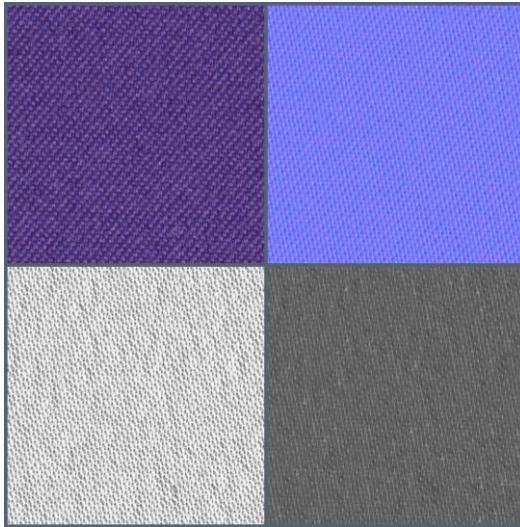


Estimating Reflectance from Microgeometry

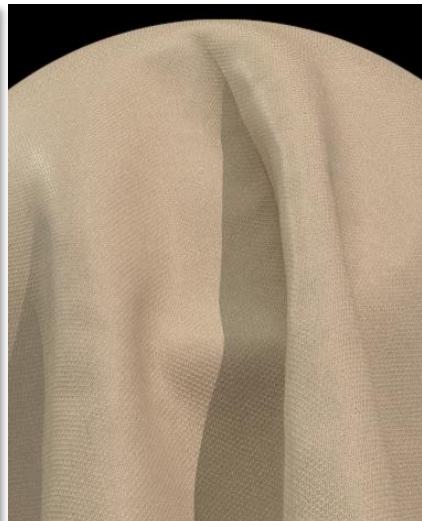
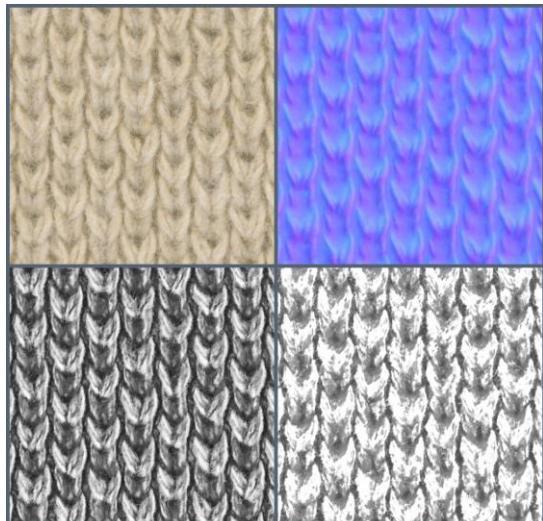
Plain (Woven)



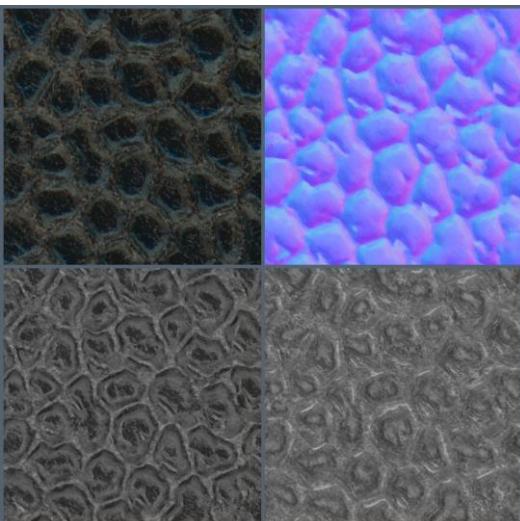
Satin (Woven)



Pique (Knit)



Leather



SVBRDF

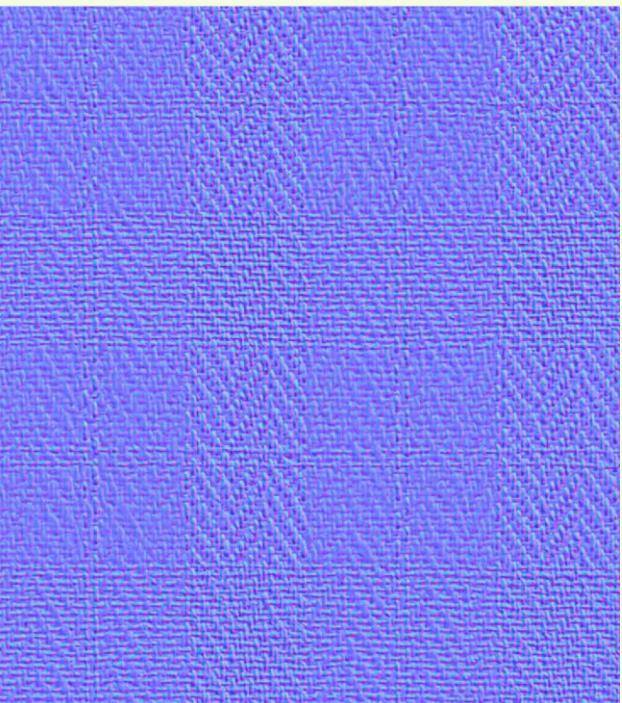
SVBRDF

Input

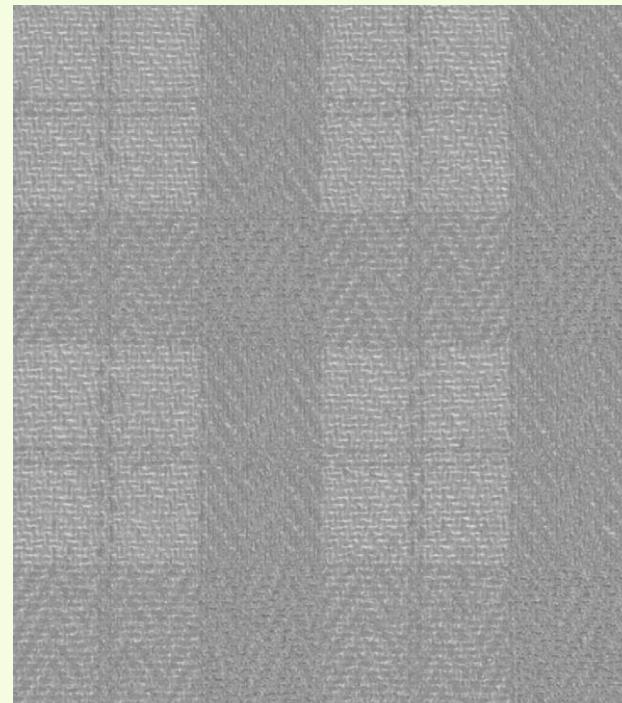


Albedo

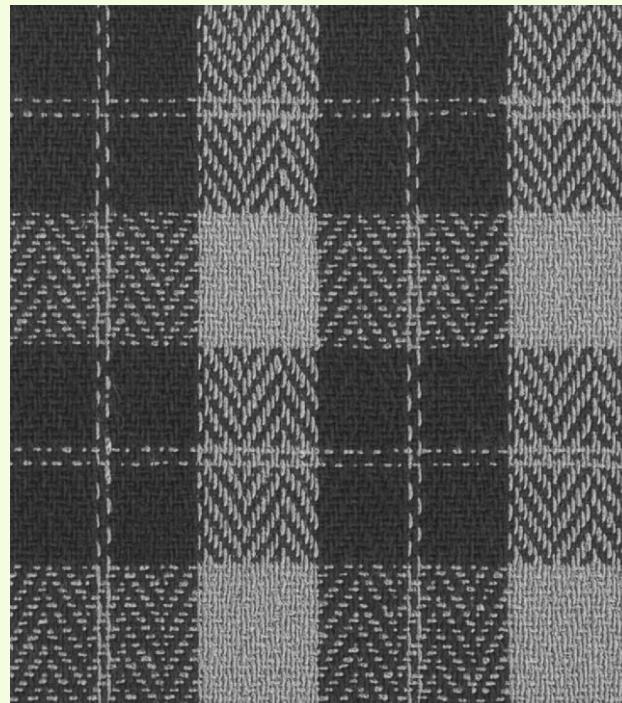
Estimated



Normals



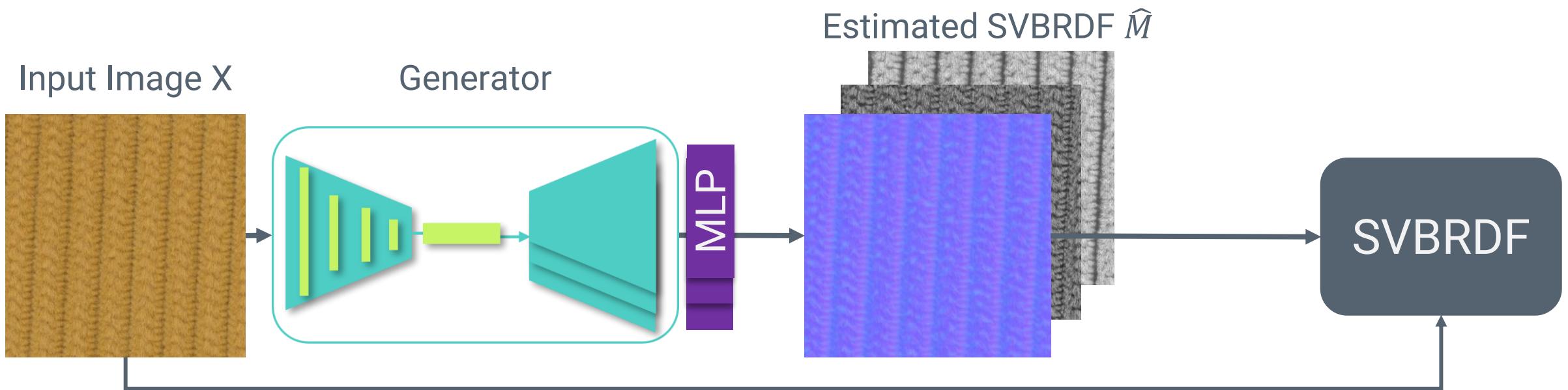
Roughness



Specular

SVBRDF

$$f_{l,v}(\mathbf{M}, \mathbf{X}) = \frac{\mathbf{X}}{\pi} + s_{l,v}(\mathbf{M}) \in \mathbb{R}^{x \times y}$$

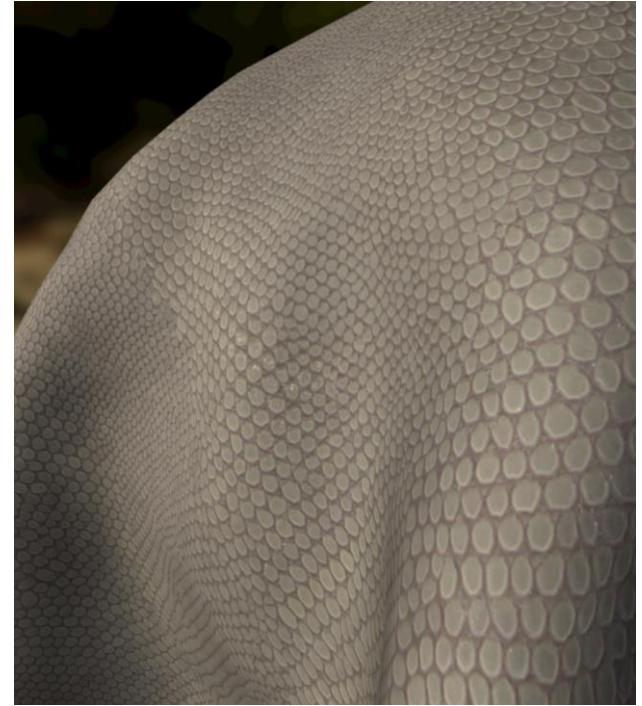


X: Albedo (Input)

M (G(X)): Normals, Roughness, Specular

SVBRDF

Only Albedo



+Normals



+Roughness

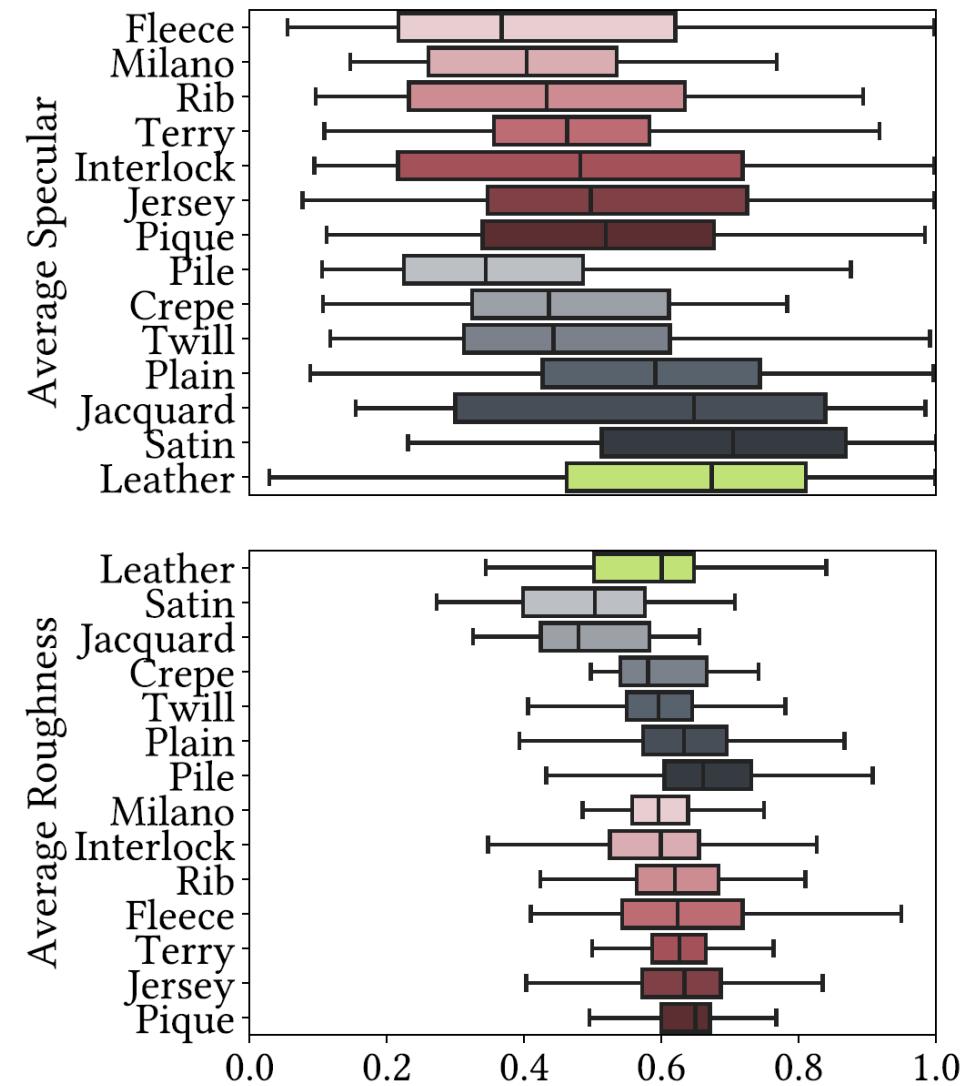
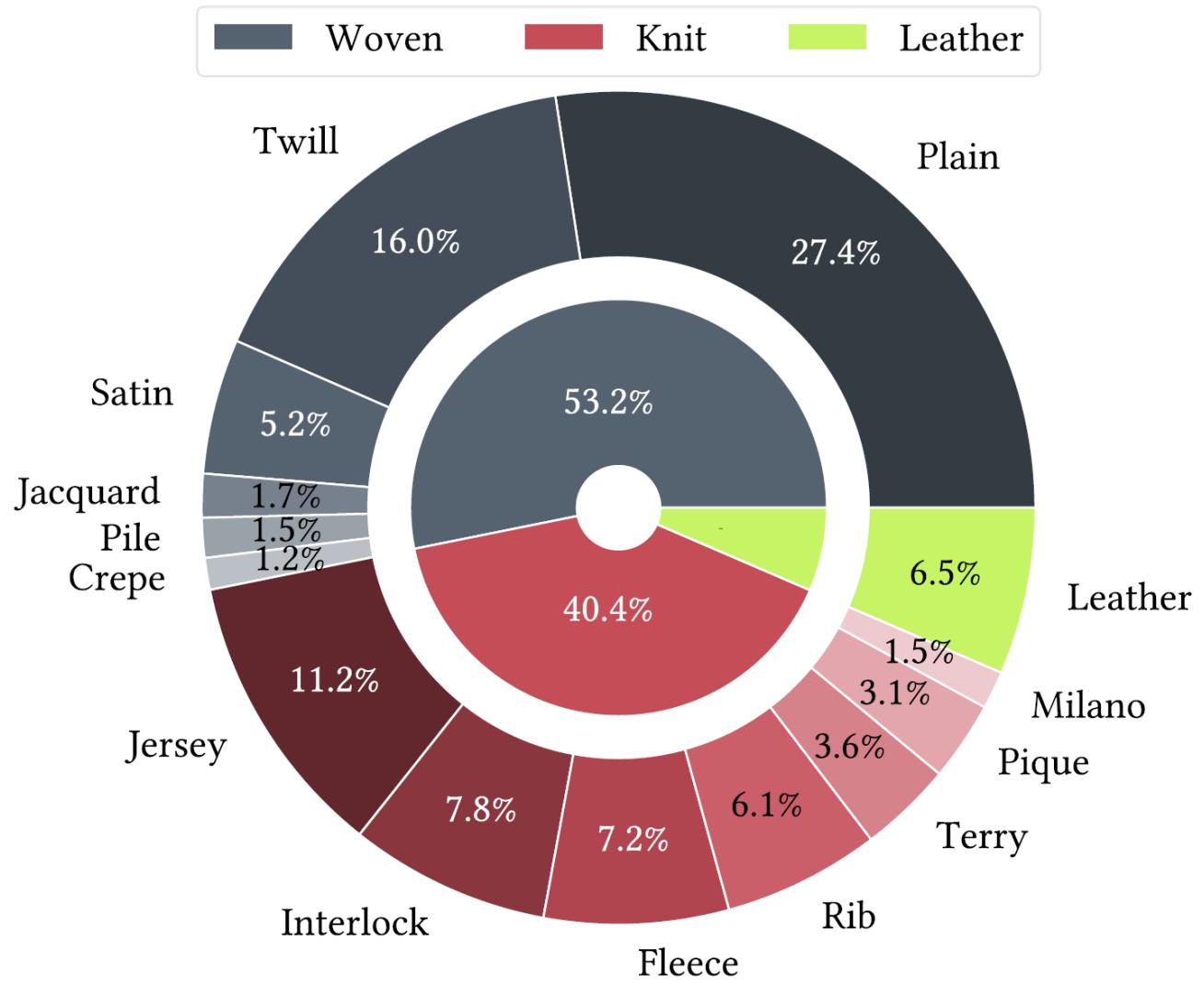


+Specular



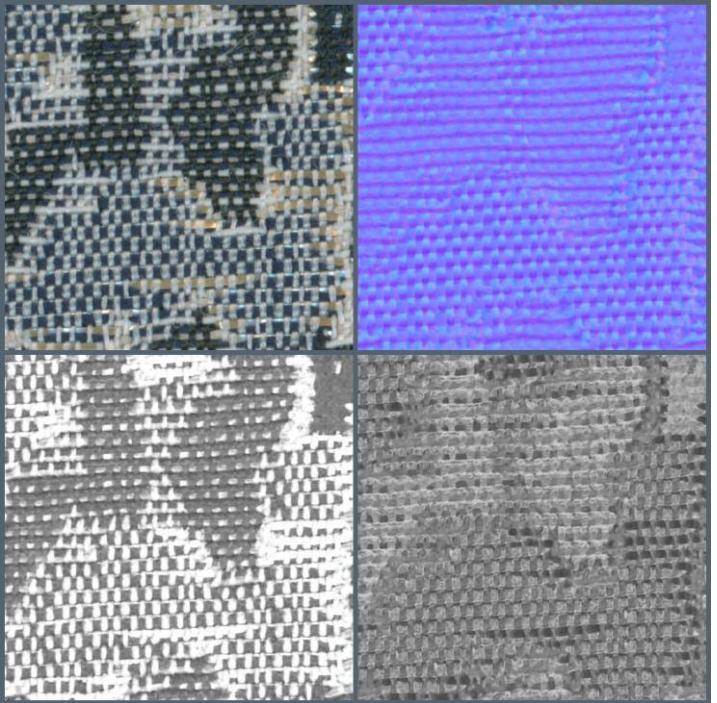
Dataset

UMat: Dataset

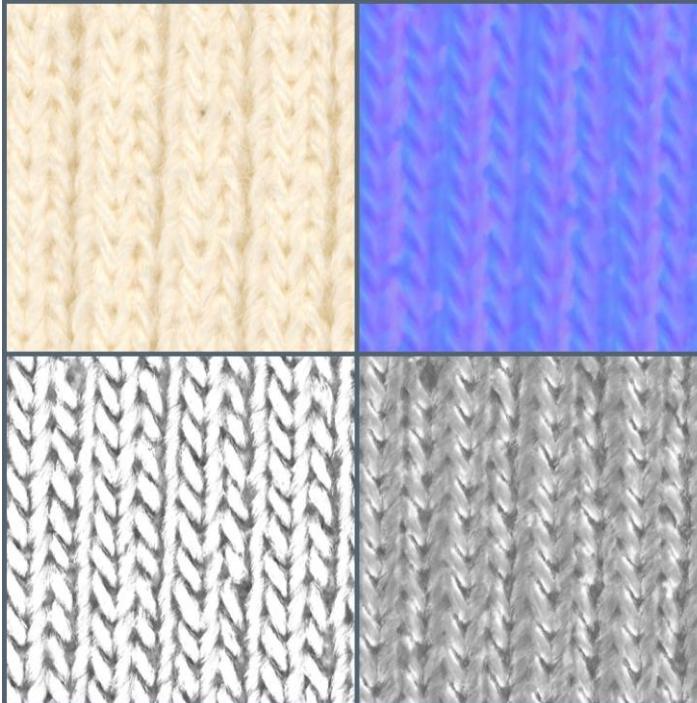


UMat: Dataset

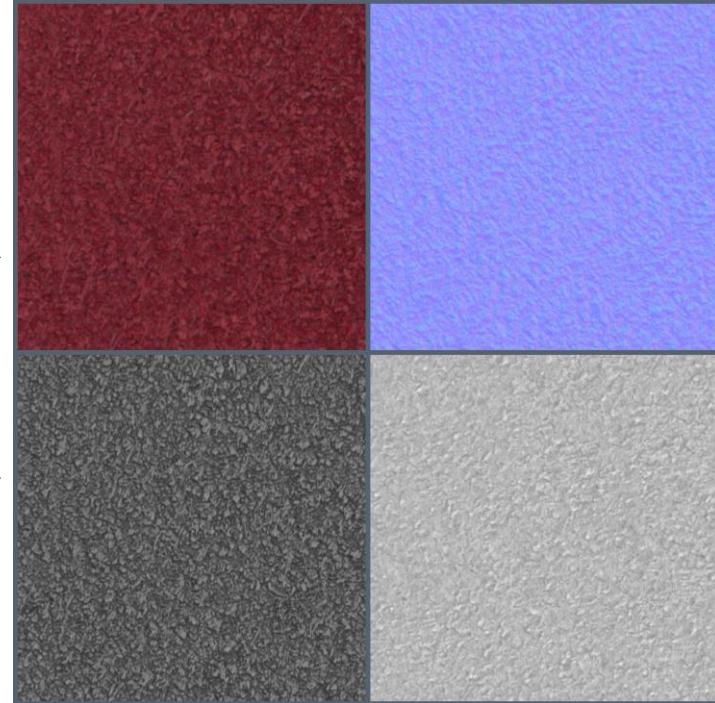
Jacquard (Woven)



Rib (Knit)



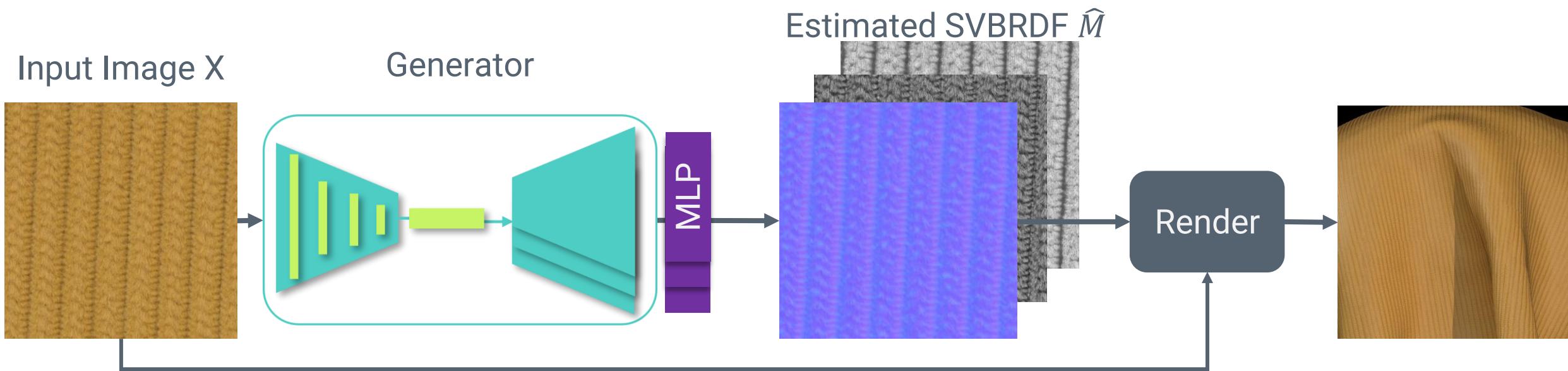
Suede (Leather)



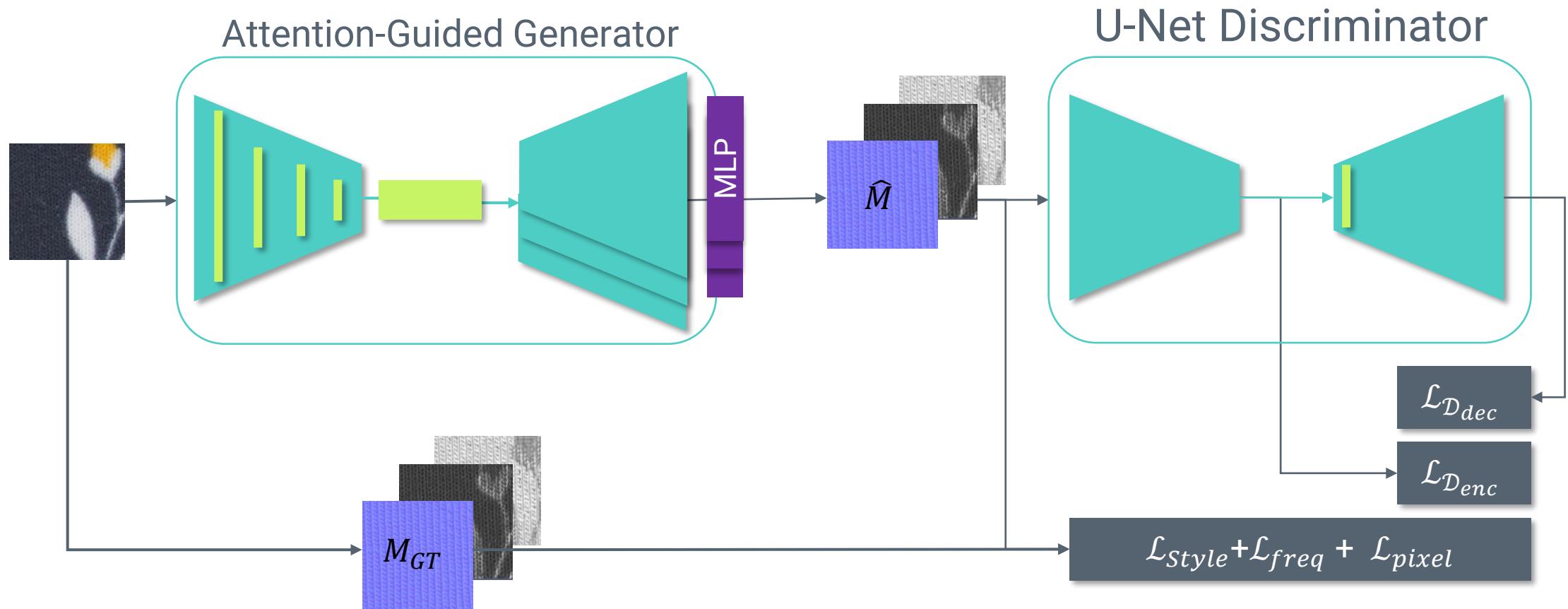
*Towards Material Digitization with a Dual-scale Optical System.
Garces et al (TOG, Proc. SIGGRAPH 2023).*

Model Design and Training

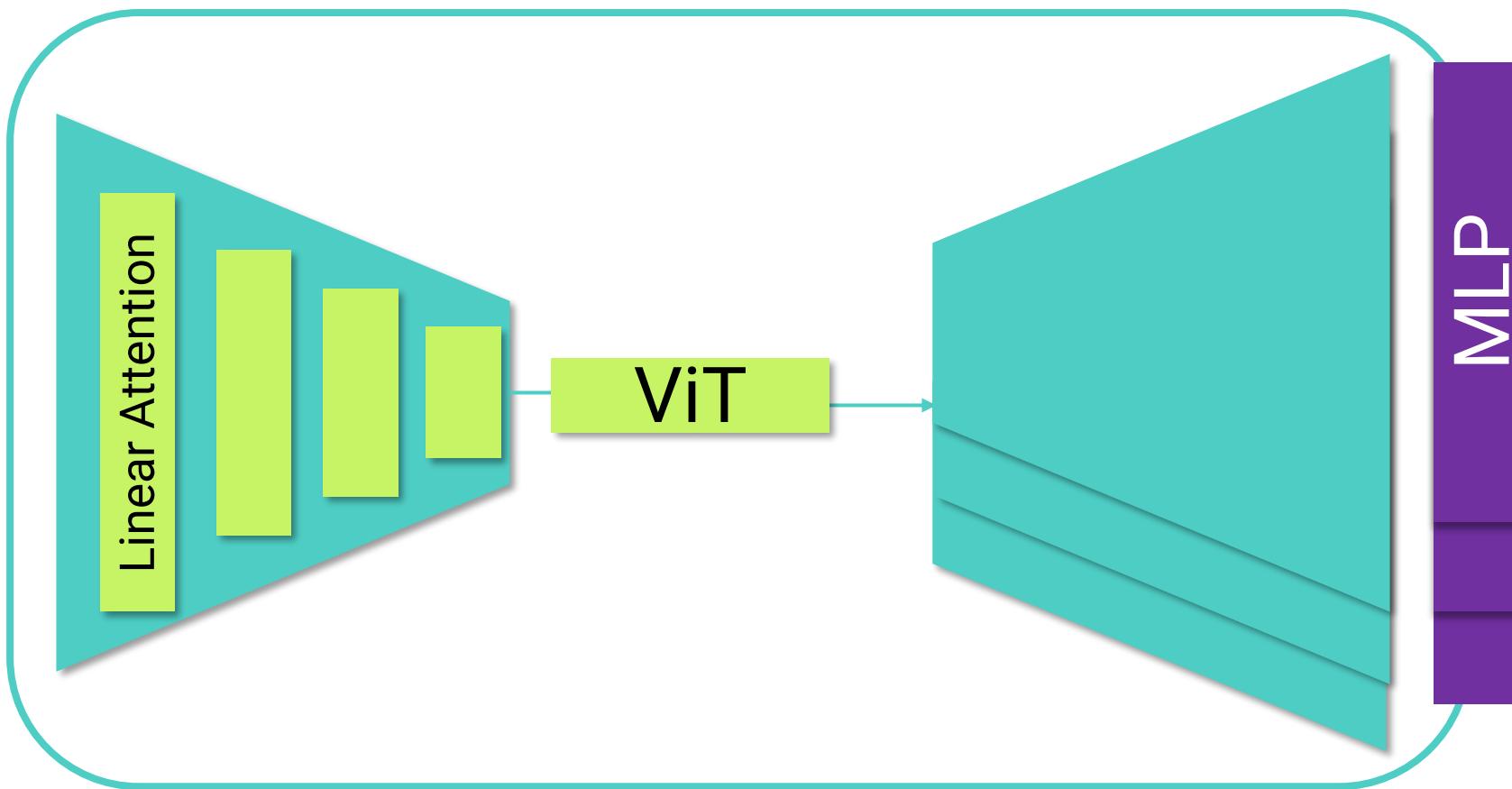
Inference



Training



Generator Architecture



Losses

$$\mathcal{L}_G = \sum_i \lambda_i \mathcal{L}_{pixel_i} + \lambda_{adv} \mathcal{L}_{adv} + \lambda_{style} \mathcal{L}_{style} + \lambda_{freq} \mathcal{L}_{freq}$$

$$\mathcal{L}_{\mathcal{D}} = \mathcal{L}_{\mathcal{D}_{enc}} + \mathcal{L}_{\mathcal{D}_{dec}} + \lambda_{cons} \mathcal{L}_{\mathcal{D}_{dec}}^{cons}$$

$$\mathcal{L}_{adv} = \log(\mathcal{D}_{enc}(G(X)) + \log(\mathcal{D}_{dec}(G(X)))$$

Pixel-wise norm for accurate maps

Style loss increases sharpness and perceptual quality

Pixel-wise and global adversarial losses for local and global quality

Frequency loss allows for better learning high-frequency patterns

Evaluation

BRDF Evaluation Error

$$\mathcal{L}_{\text{BRDF}} = \frac{1}{|xy|} \sum_{xy} \sqrt{\frac{1}{|S|} \sum_{(l,v) \in S} \sqrt[3]{\cos^2(\theta_l)} \left(f_{l,v}(\mathbf{M}_{GT}, K) - f_{l,v}(\hat{\mathbf{M}}, K) \right)^2}$$

Average render distance between M_{GT} and estimated \hat{M}

We render $f_{l,v}$ the SVBRDFs at a set of optimized light and view positions

We use a grayscale albedo K to isolate the impact of the other parameters

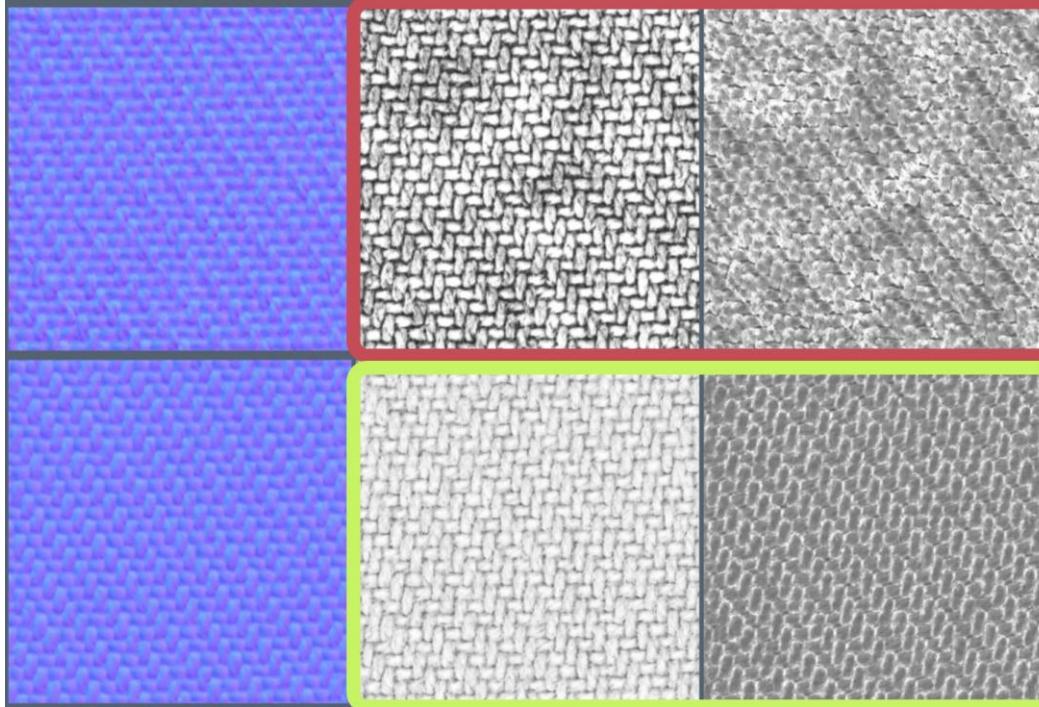
Perceptually Motivated: Specular Peak attenuation, Cosine Weighting

Artifact Detection

Input Image



Estimation with artifacts

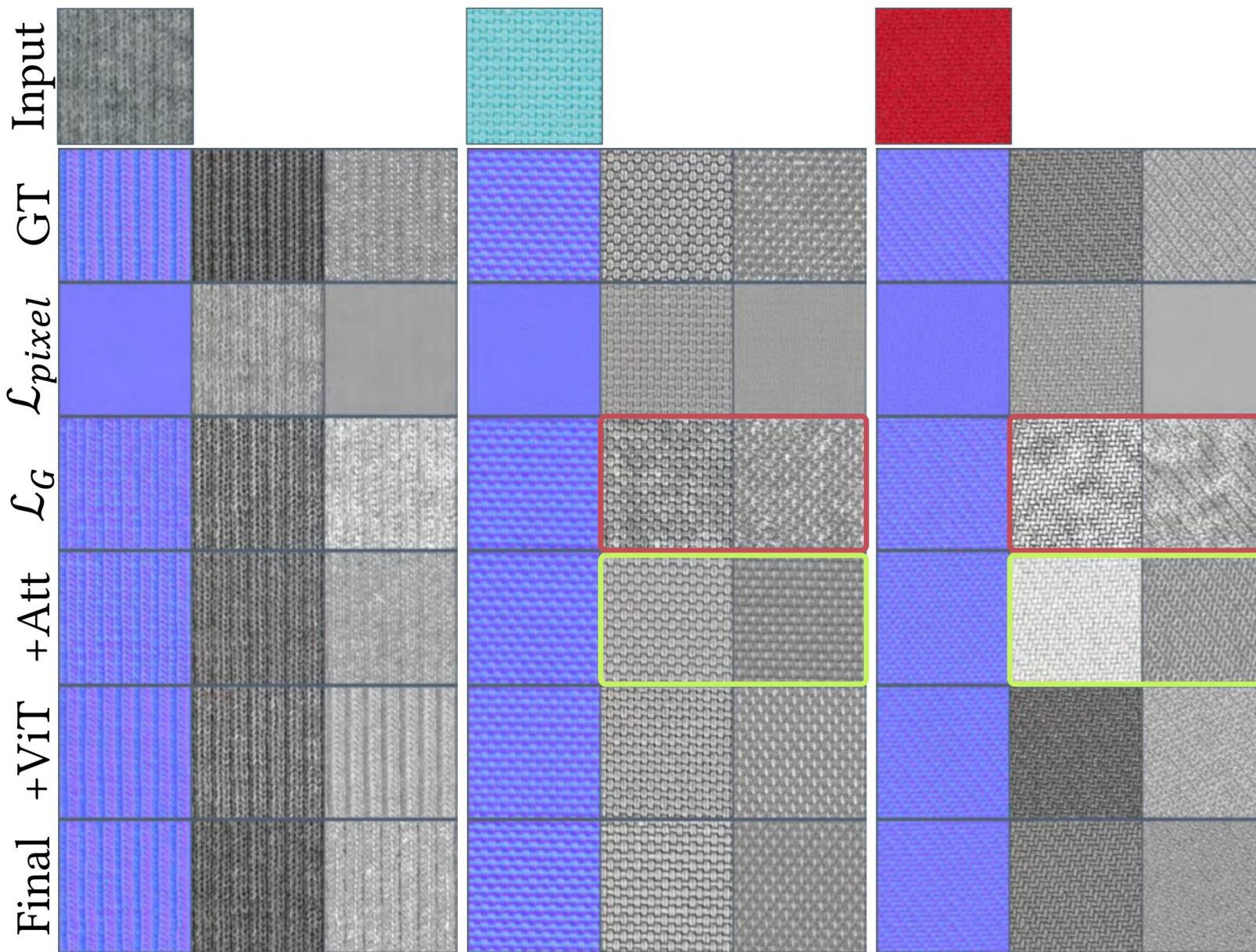


Artifact-free estimation

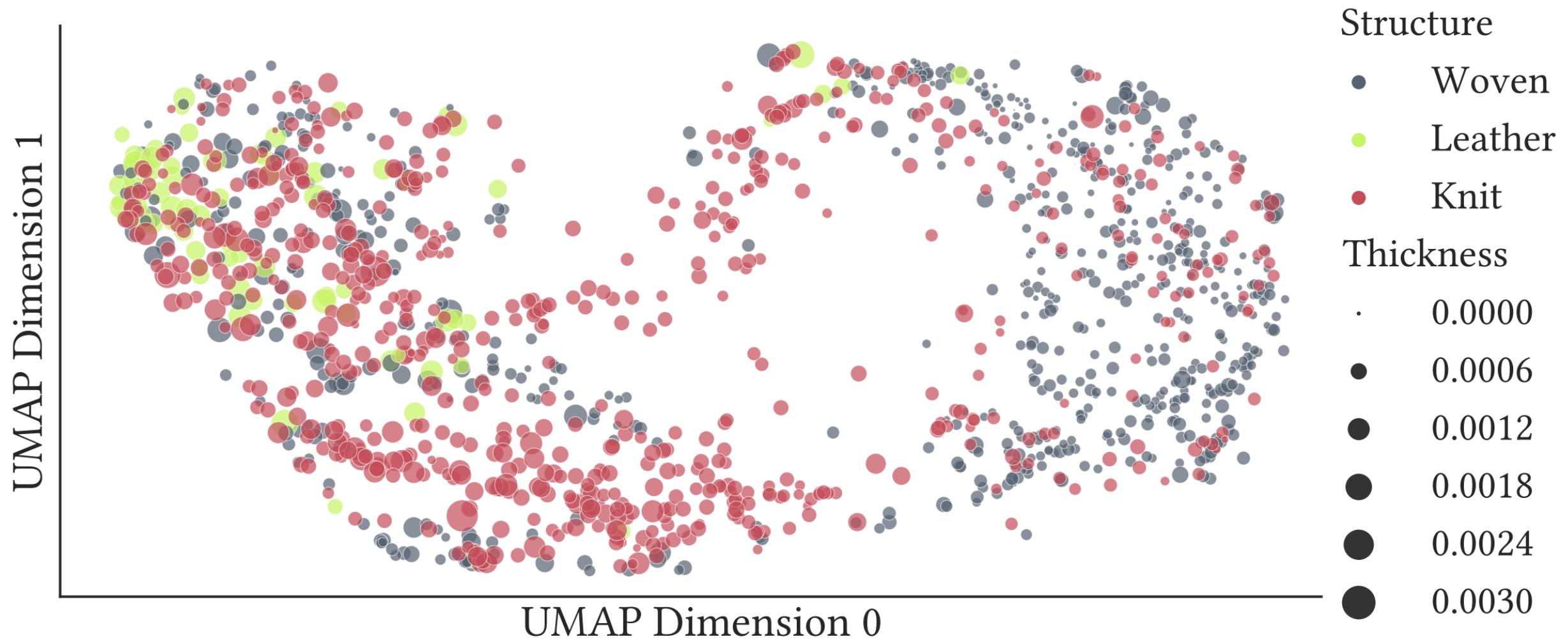
Mutual information for automatic artifact detection

$$\mathcal{H}(\mathbf{I}) = \frac{1}{|xy|} \sum_{xy} \frac{1}{|d|} \sum_{d=\{\uparrow, \downarrow, \leftarrow, \rightarrow\}} \|F_{\text{Box}}(\mathbf{I}) - F_{\text{Box}}(\mathbf{I}^d)\|_1$$

UMat: Qualitative Ablation

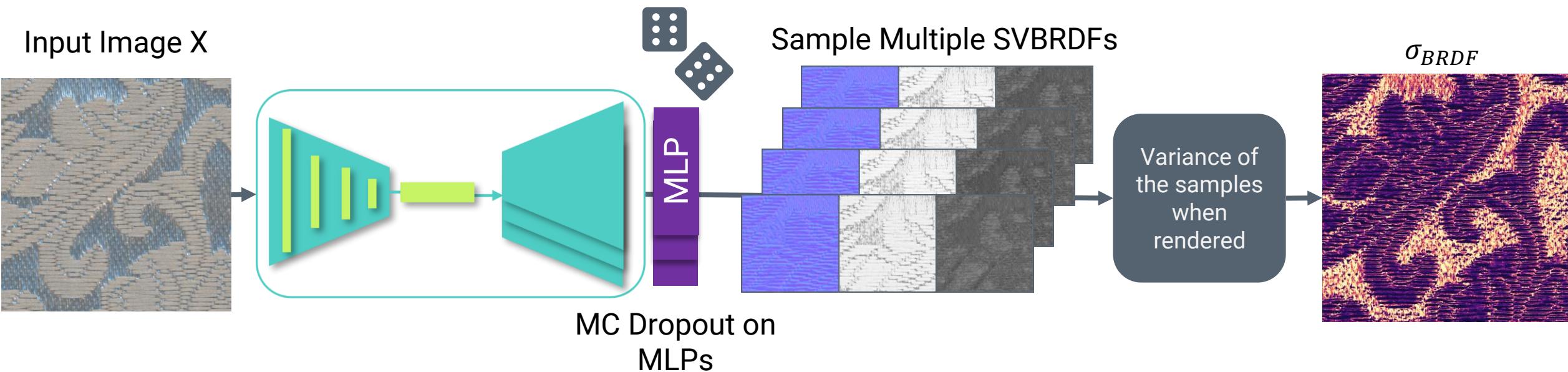


Latent Embeddings



Uncertainty Quantification

Uncertainty Estimation: Our Approach



Uncertainty Estimation: Our Approach

$$\sigma_{\text{BRDF}} = \frac{1}{|xy|} \sum_{xy} \log \left(\frac{1}{|S|} \sqrt{\sum_{(l,v) \in S} \sqrt[3]{\sigma_{l,v}(\{f_{l,v}(U_j, K) \cos(\theta_l)\}_{j=1}^N)}} \right)$$

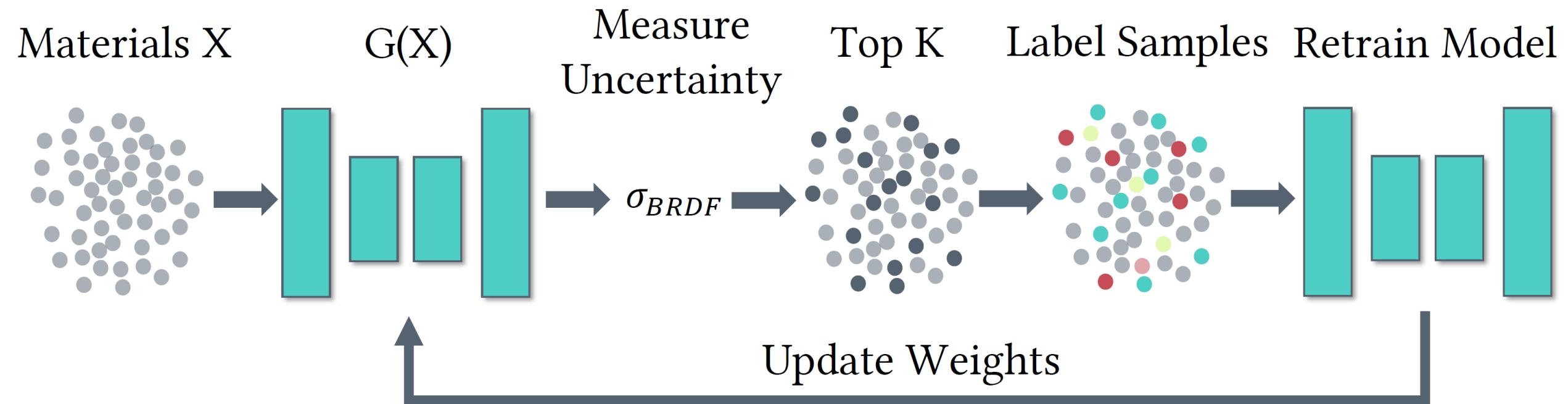
We sample a set (\mathbf{U}) of estimations using **Monte Carlo Dropout** on the MLPs.

We render $f_{l,v}$ using a grayscale albedo \mathbf{K}

Perceptually Motivated: Specular Peak attenuation, Cosine Weighting

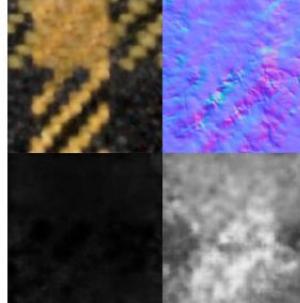
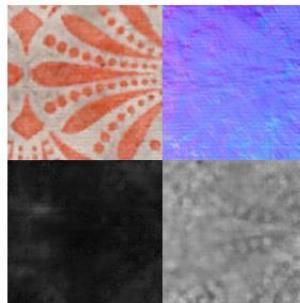
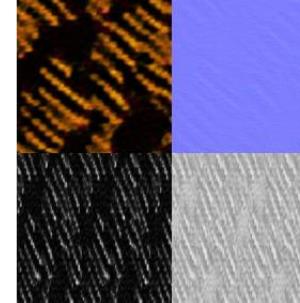
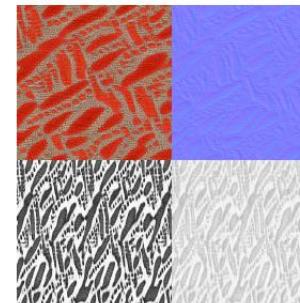
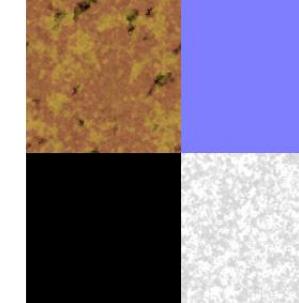
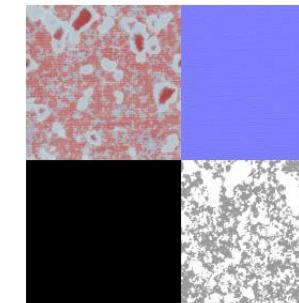
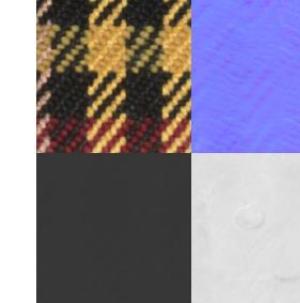
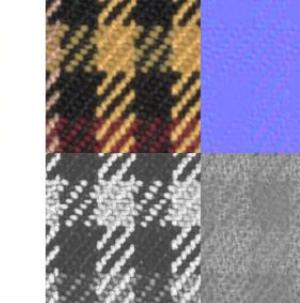
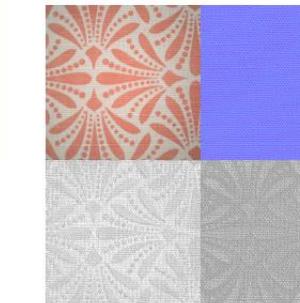
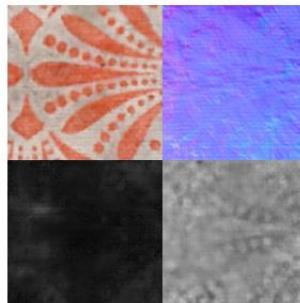
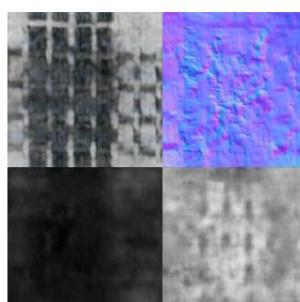
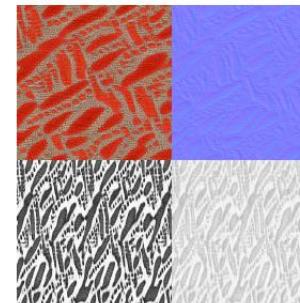
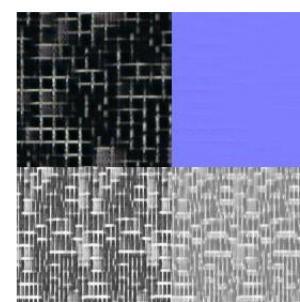
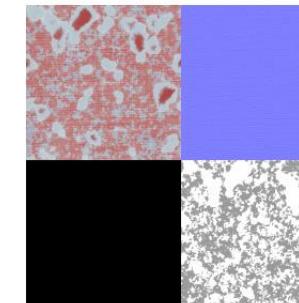
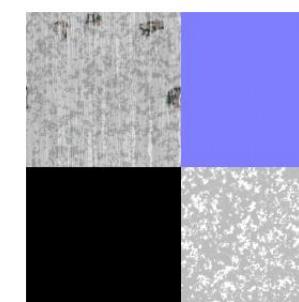
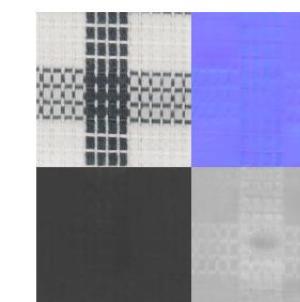
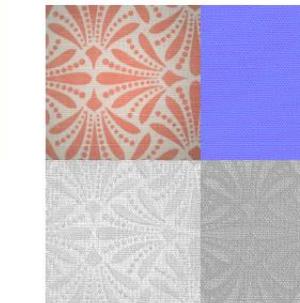
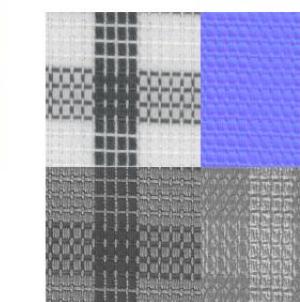
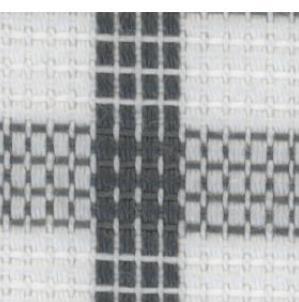
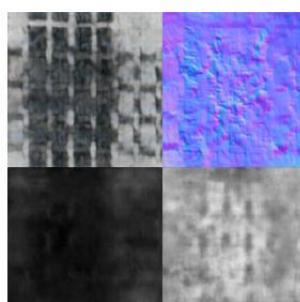
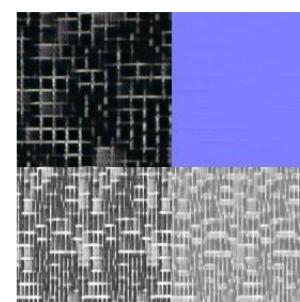
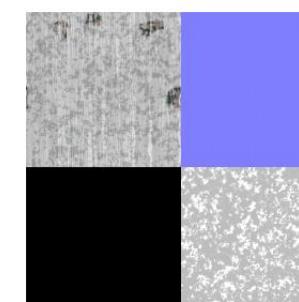
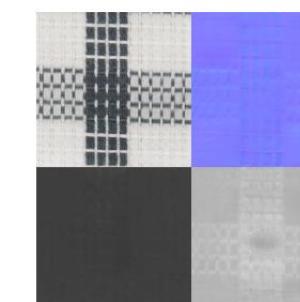
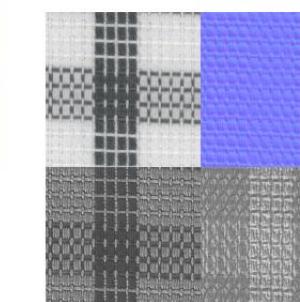
Variance across renders generated at a set of light (\mathbf{l}) and cameras (\mathbf{v}) positions

Application: Active Learning

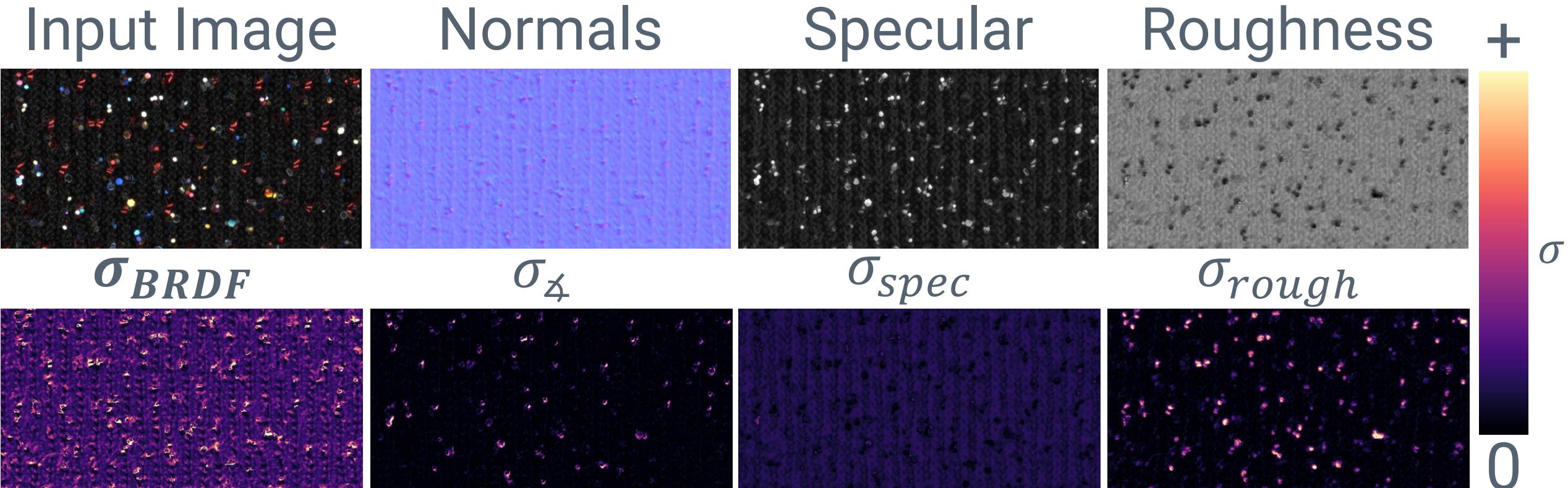


Results

UMat: Comparisons with Previous Work

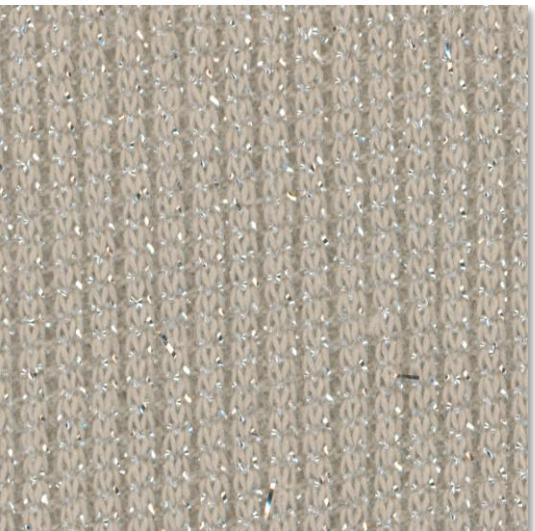
	Input	Deep Inverse Rendering [11]	Generative Modeling [21]	Diff. Material Graphs [59]	Adversarial Estimation [74]	UMat (Ours)
Smartphone, Flash		 	 	 	 	 
Smartphone, Ambient		 	 	 	 	 
Scanner		 	 	 	 	 

Uncertainty Quantification: Results

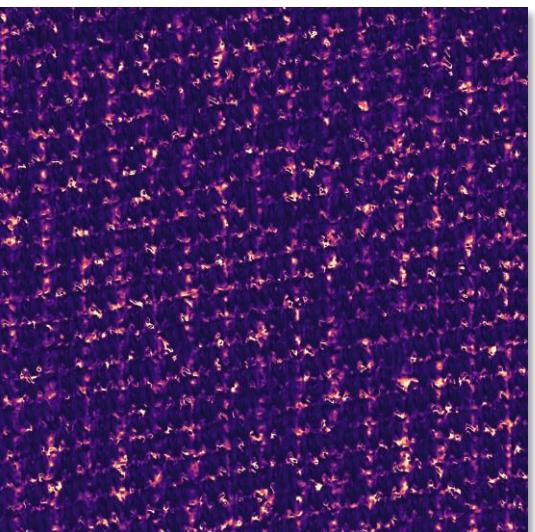


Uncertainty Quantification: Results

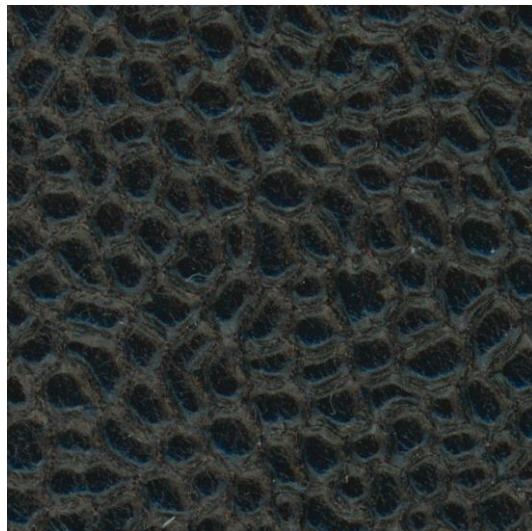
Metallic yarns



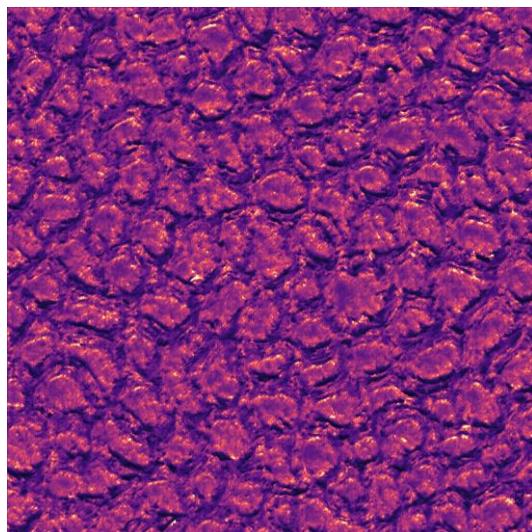
σ_{BRDF}



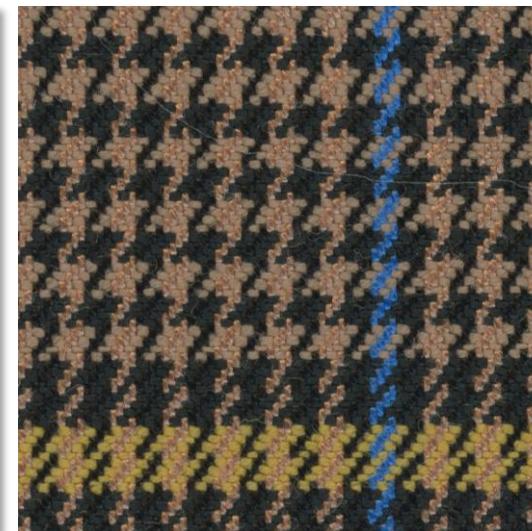
Leather



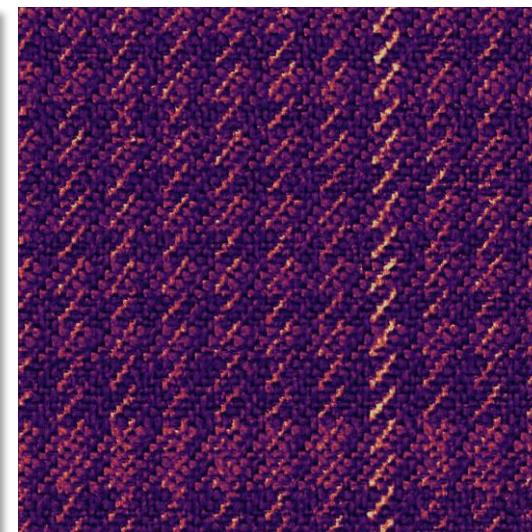
σ_{BRDF}



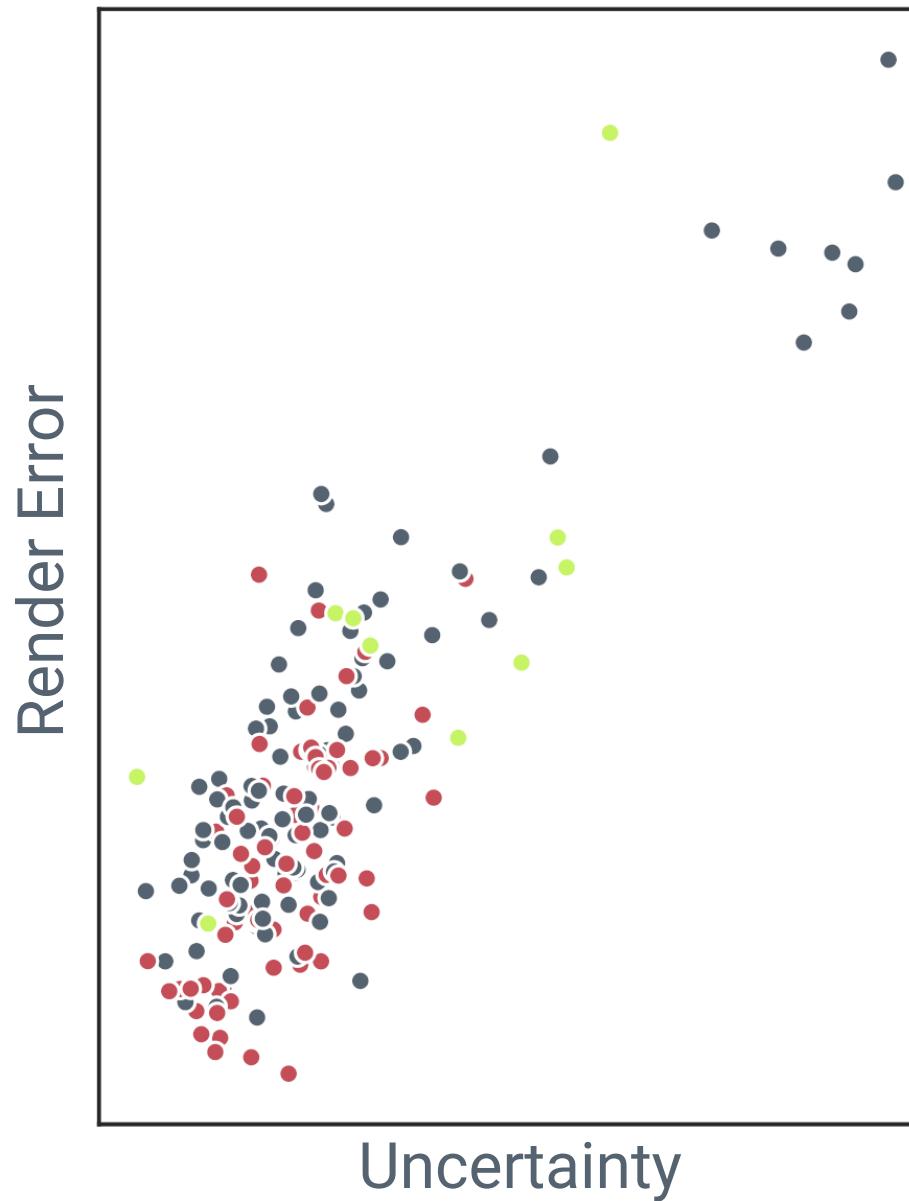
Tartan



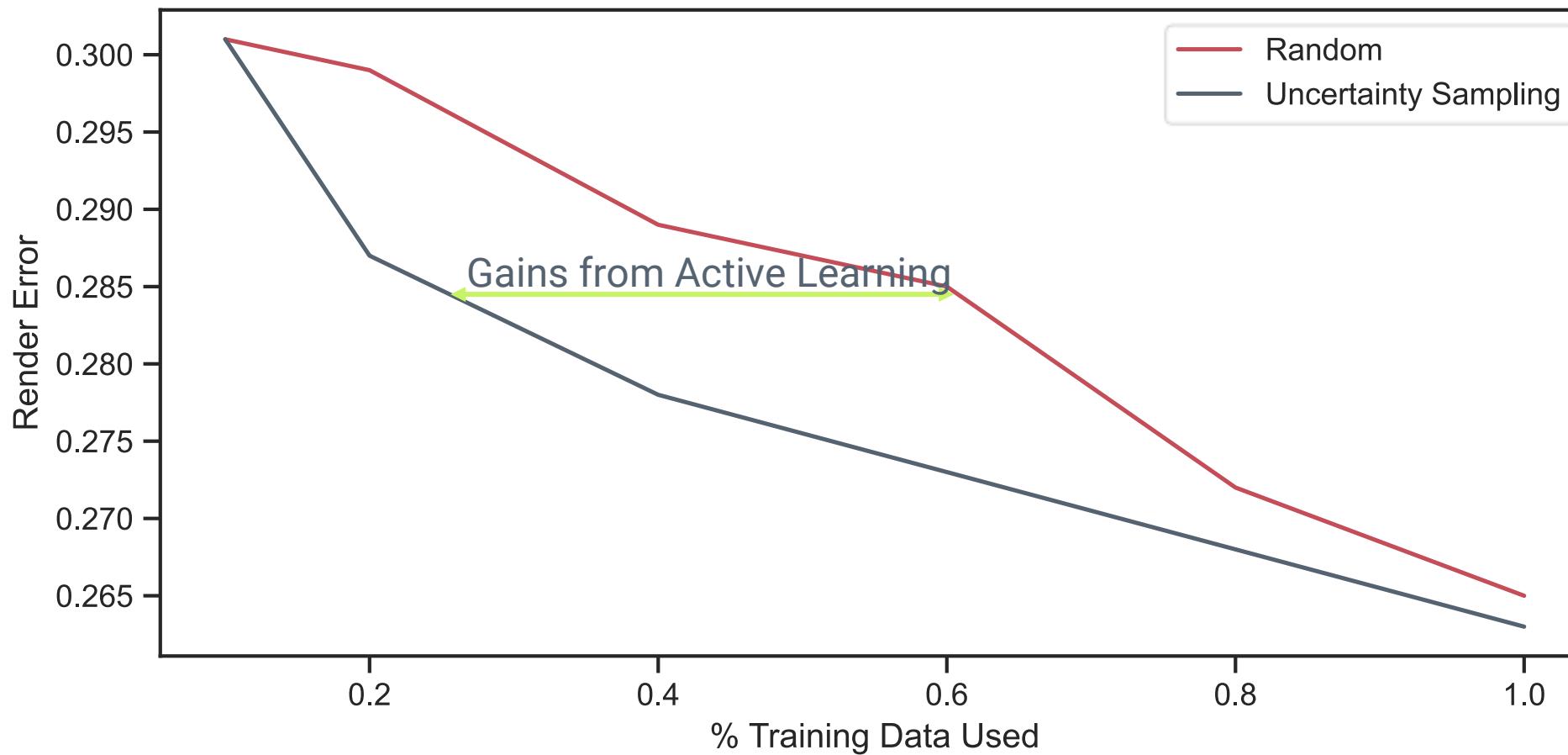
σ_{BRDF}



Uncertainty Quantification: Results

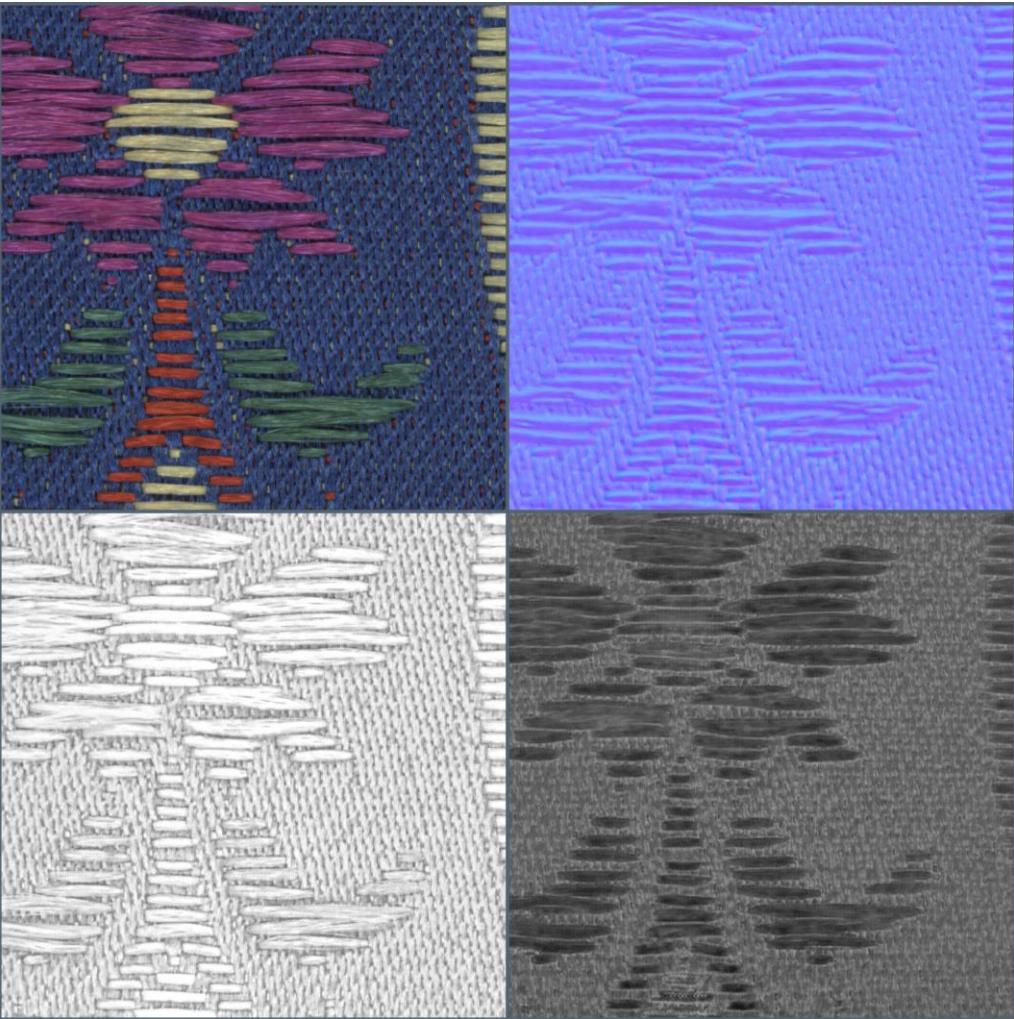


Active Learning: Results

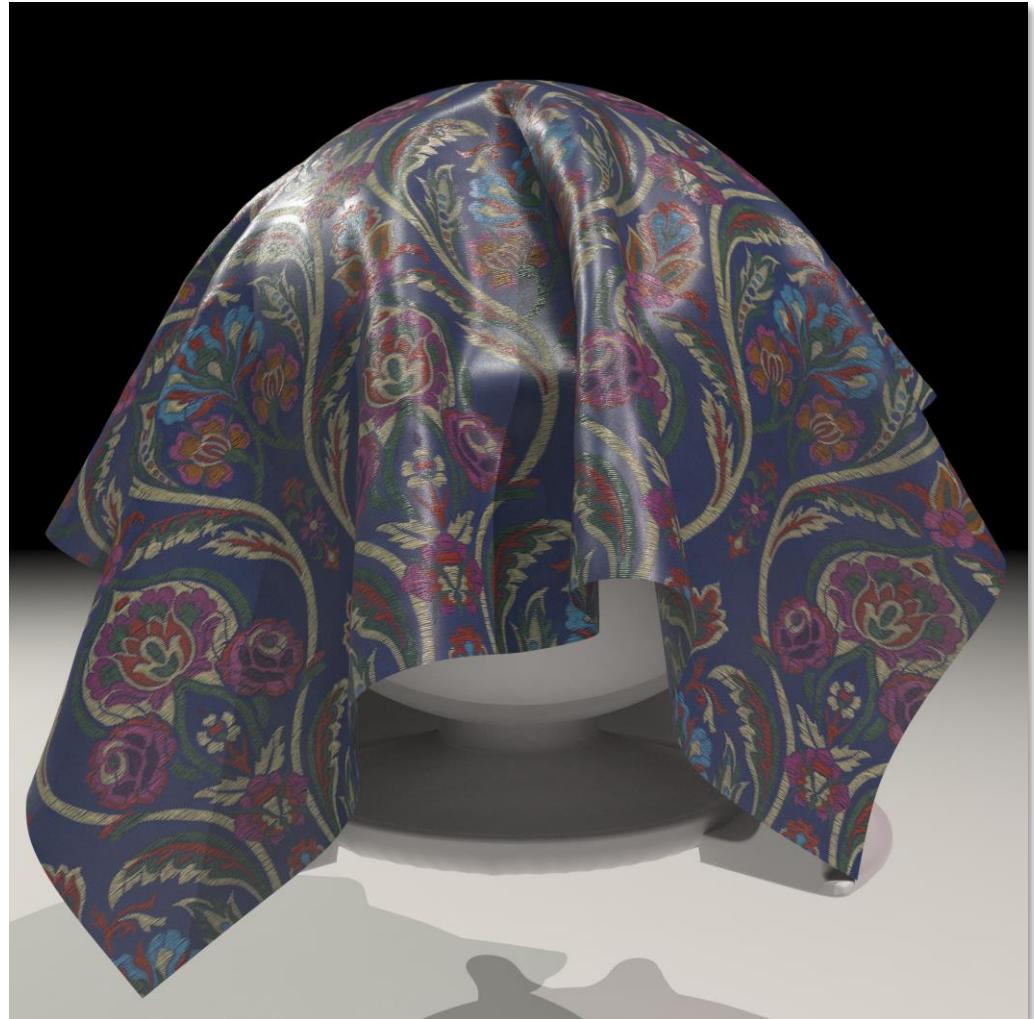


Qualitative Results

1000 PPI SVBRDF estimation (2x2 cm crop)

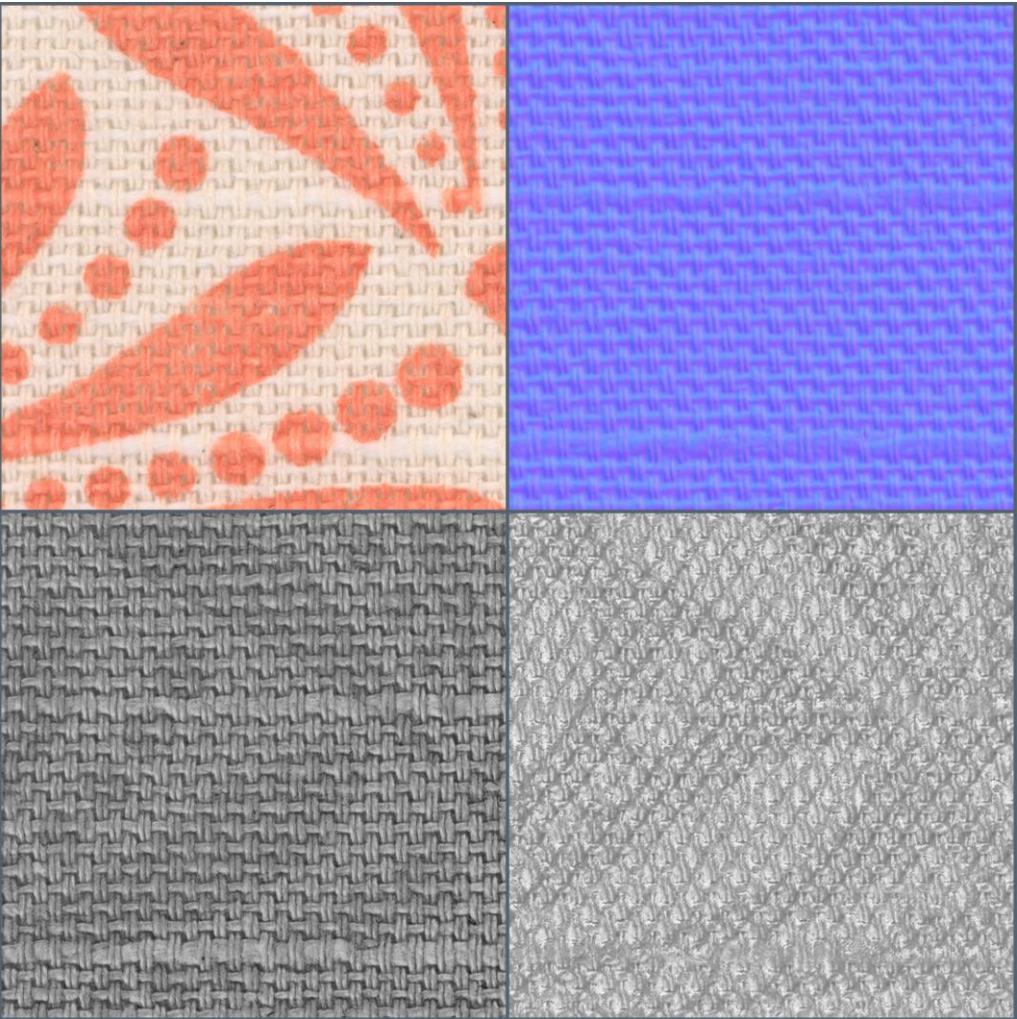


Render



Qualitative Results

1000 PPI SVBRDF estimation (2x2 cm crop)



Render

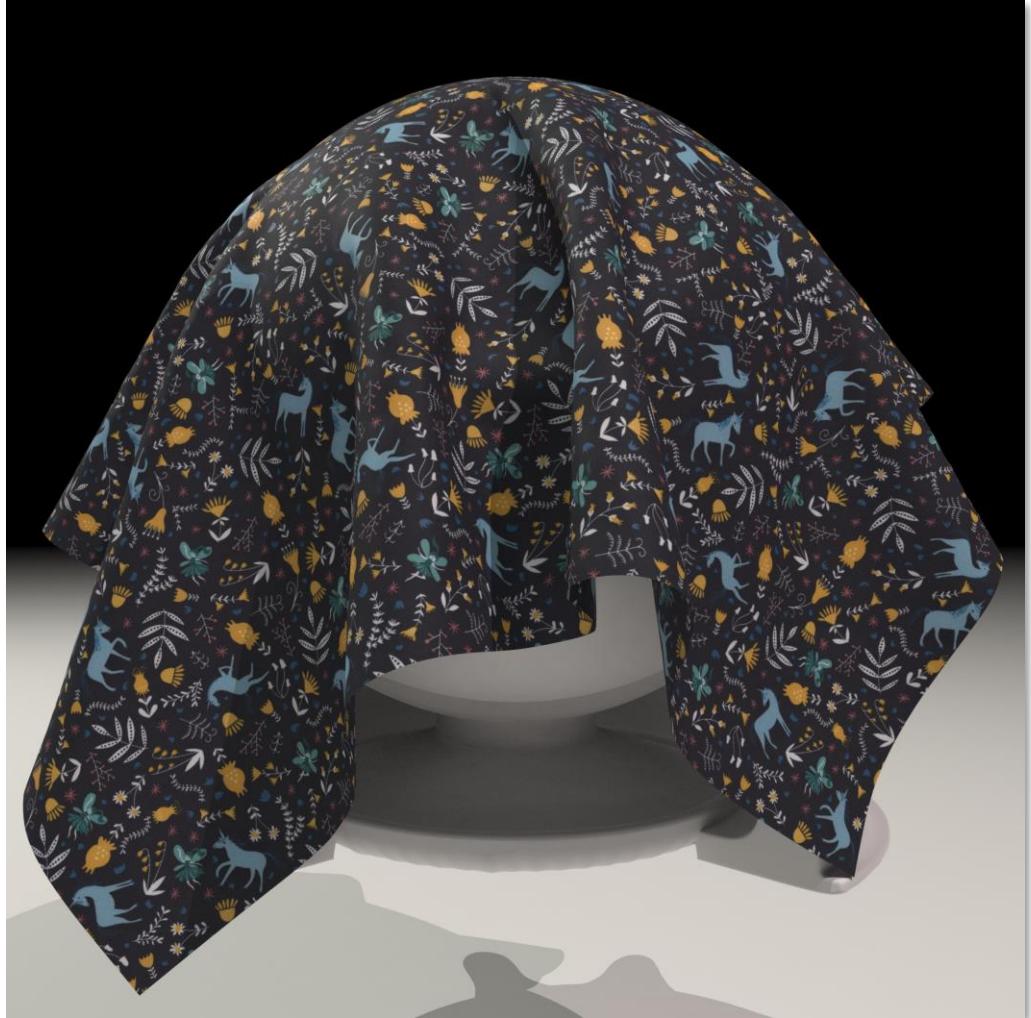


Qualitative Results

1000 PPI SVBRDF estimation (2x2 cm crop)

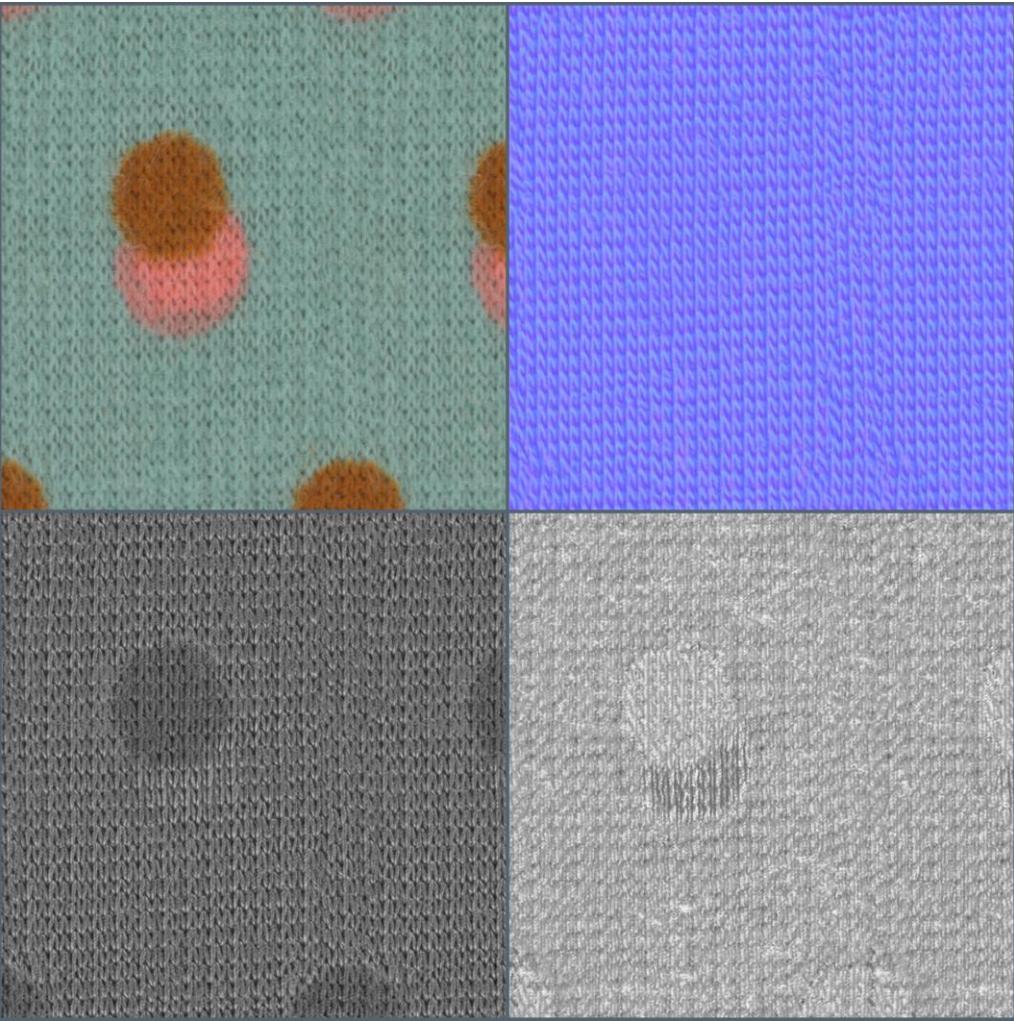


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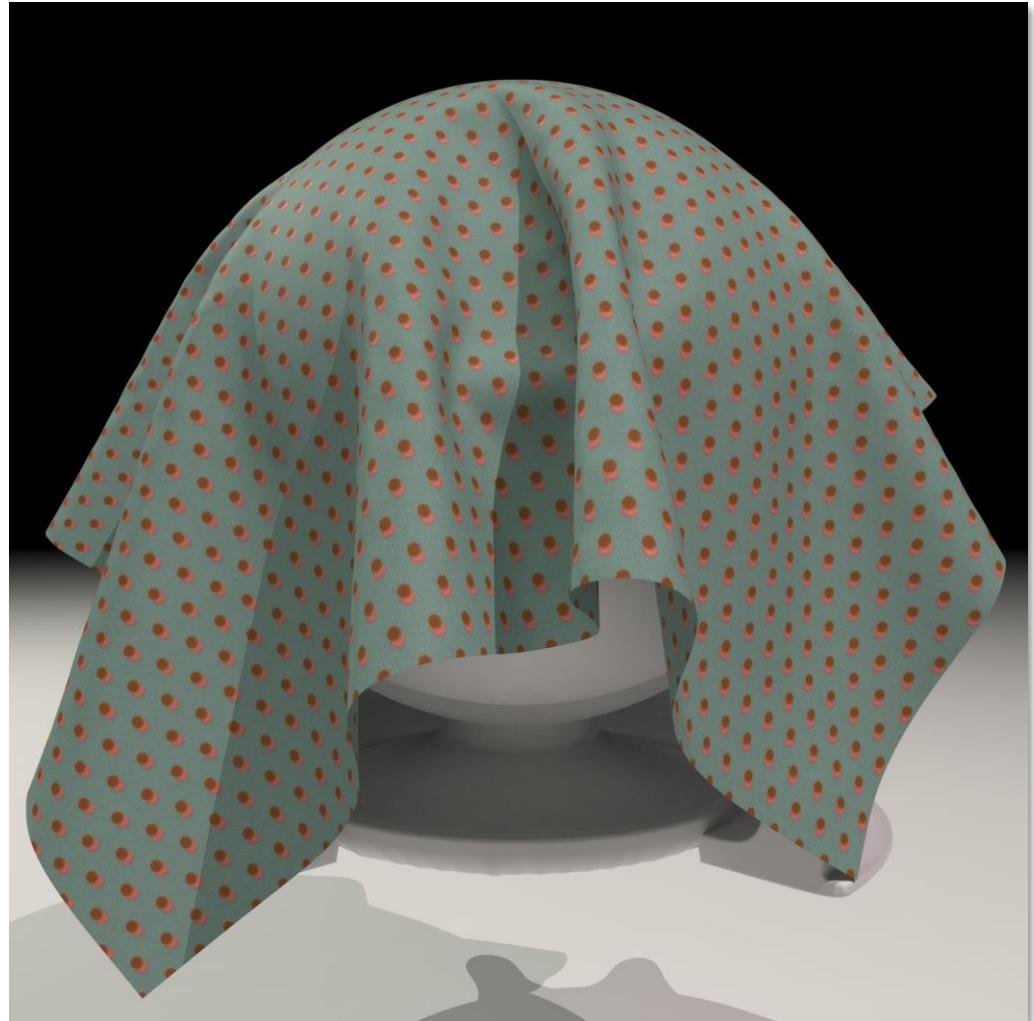


Qualitative Results

1000 PPI SVBRDF estimation (2x2 cm crop)

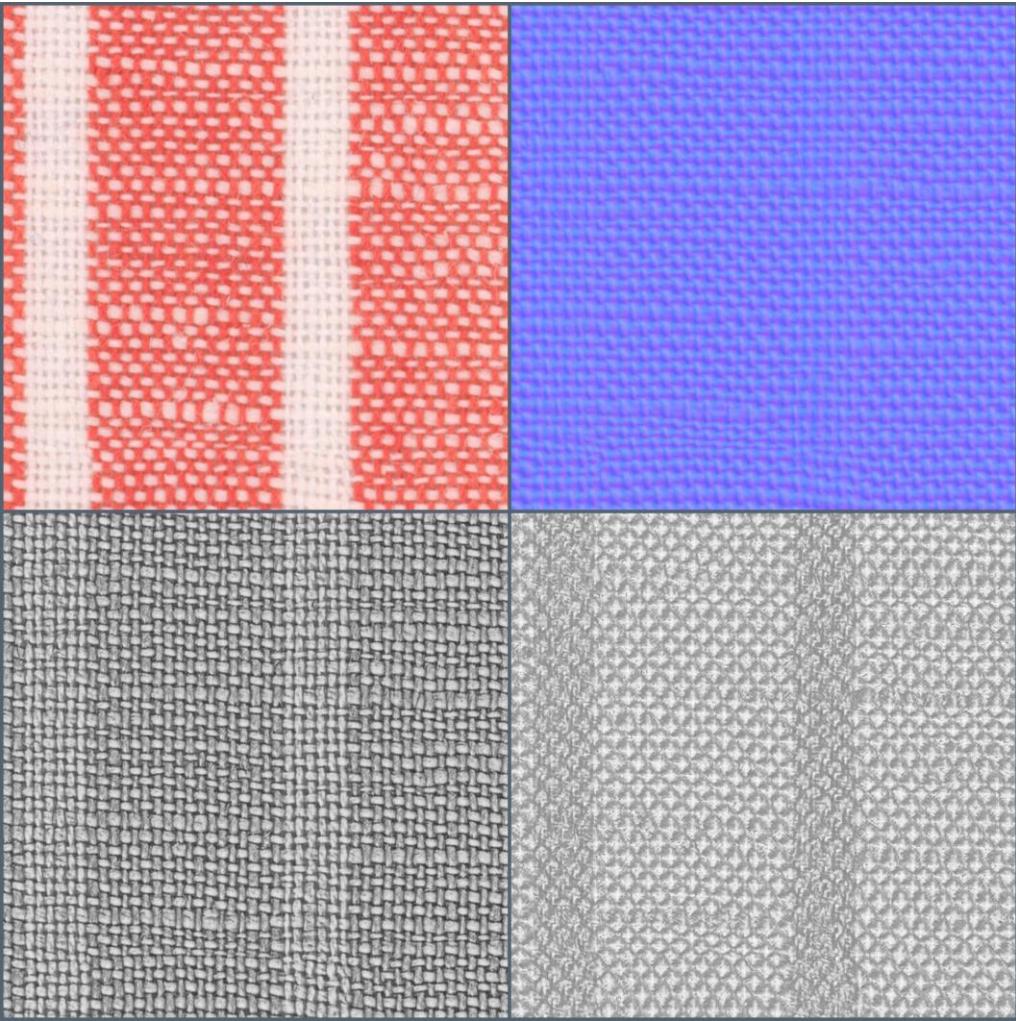


Render

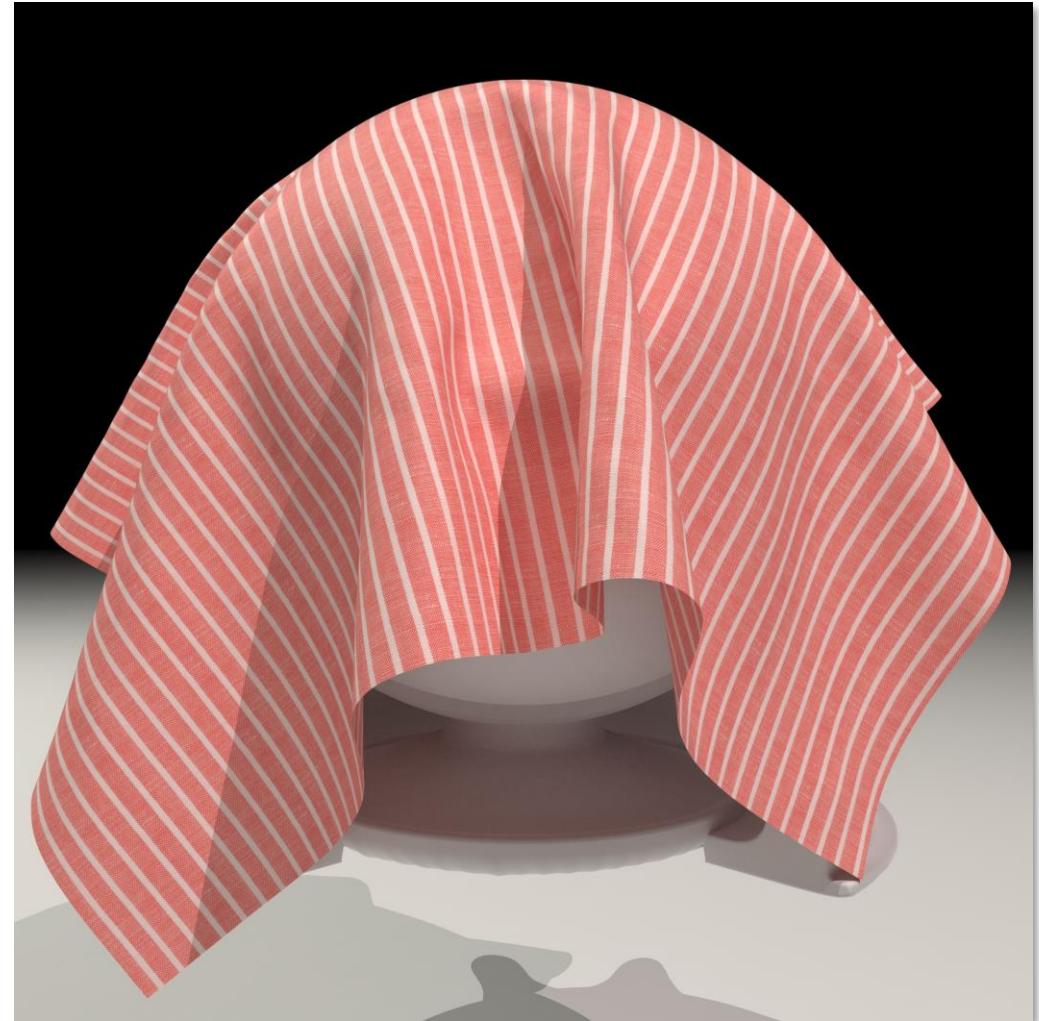


Qualitative Results

1000 PPI SVBRDF estimation (2x2 cm crop)

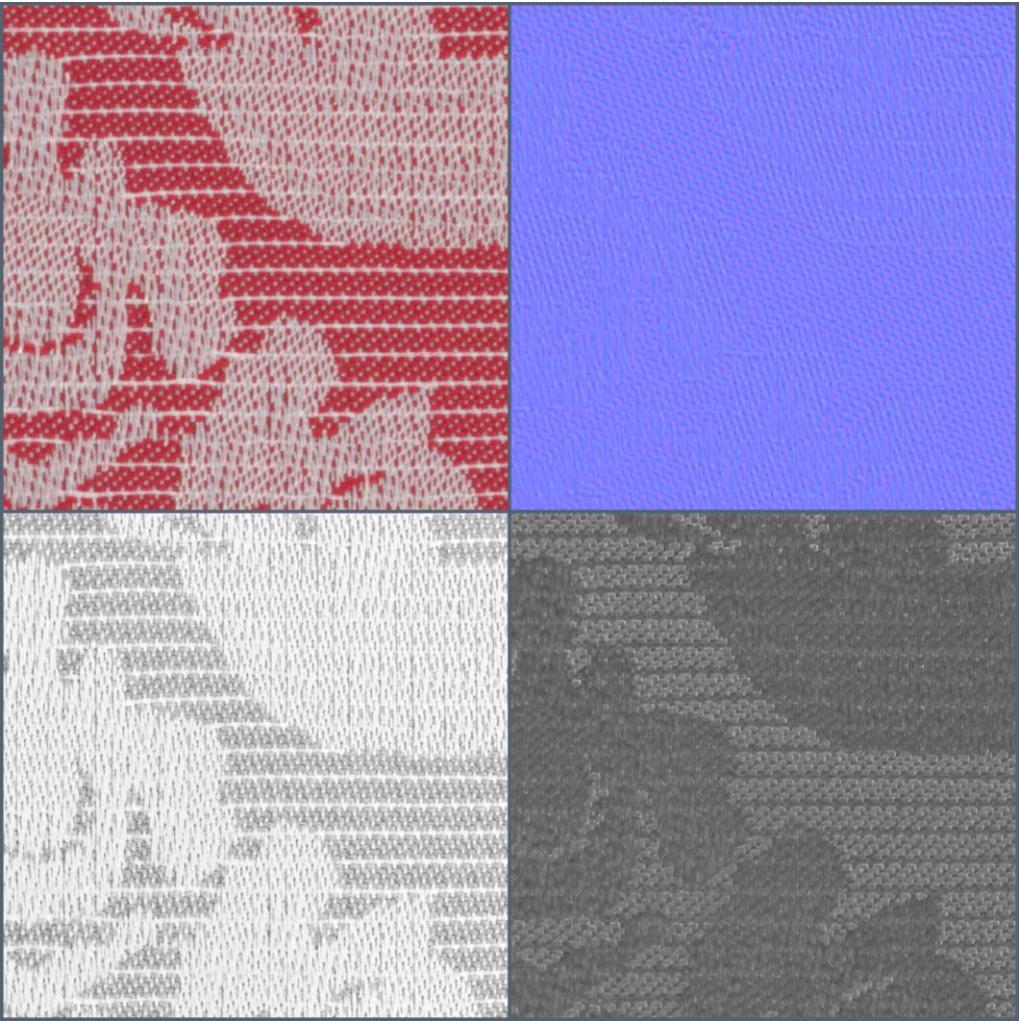


Render



Qualitative Results

1000 PPI SVBRDF estimation (2x2 cm crop)

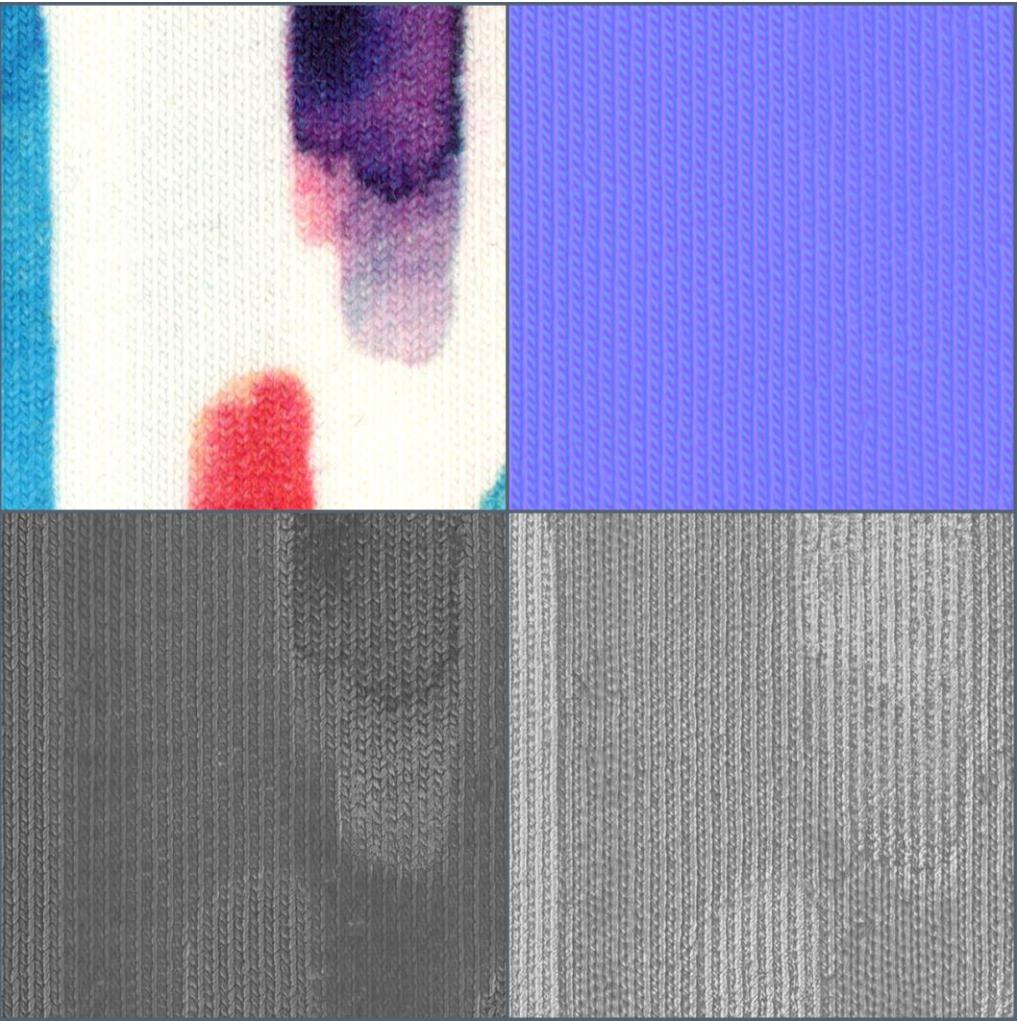


Render

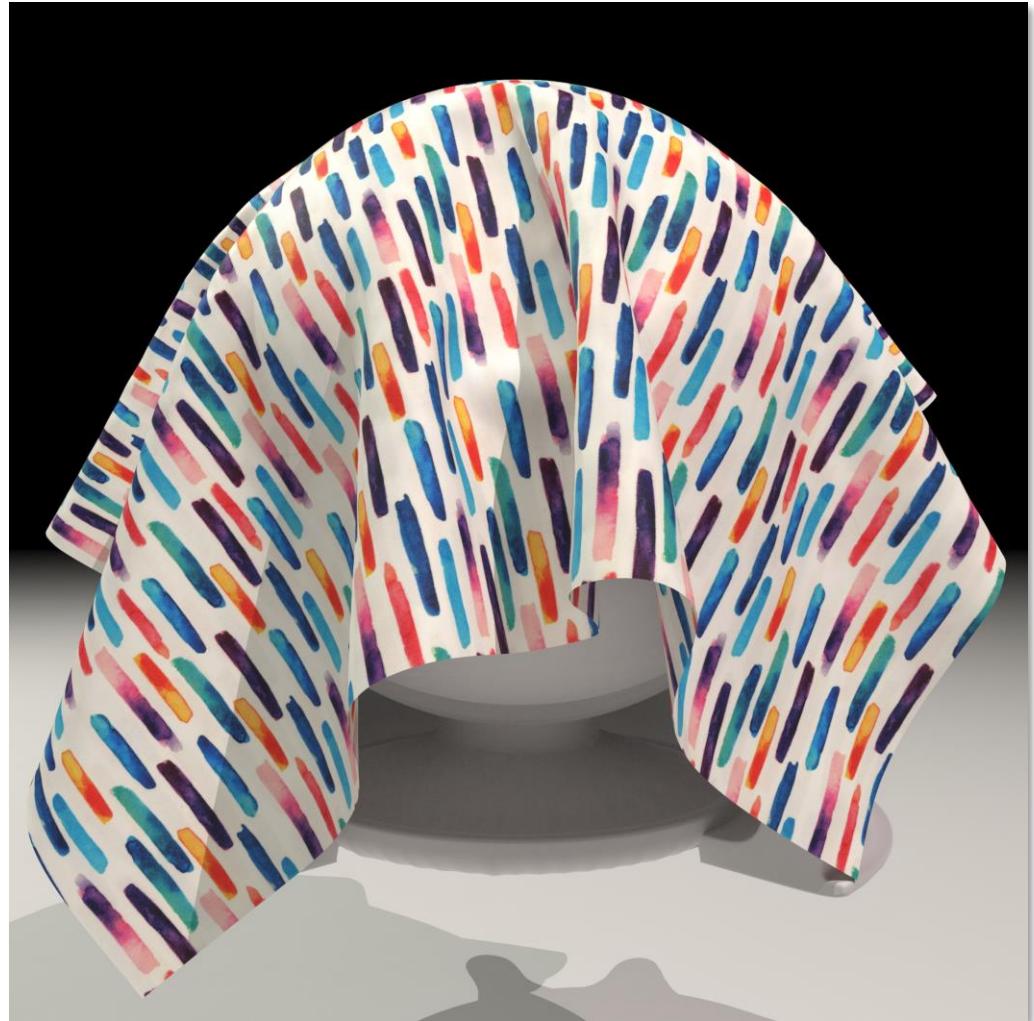


Qualitative Results

1000 PPI SVBRDF estimation (2x2 cm crop)



Render

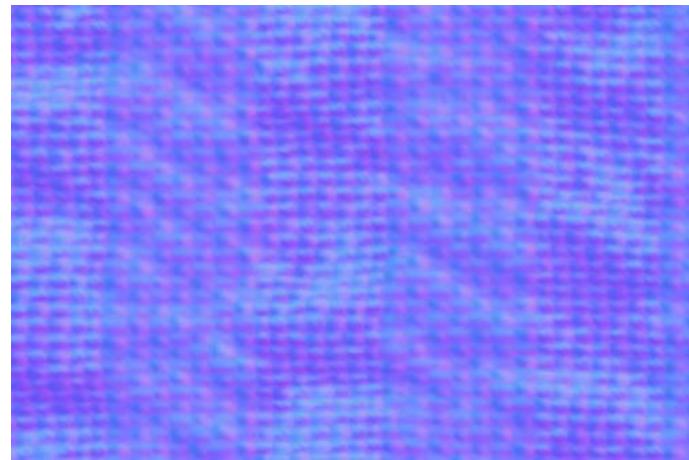


Failure Cases

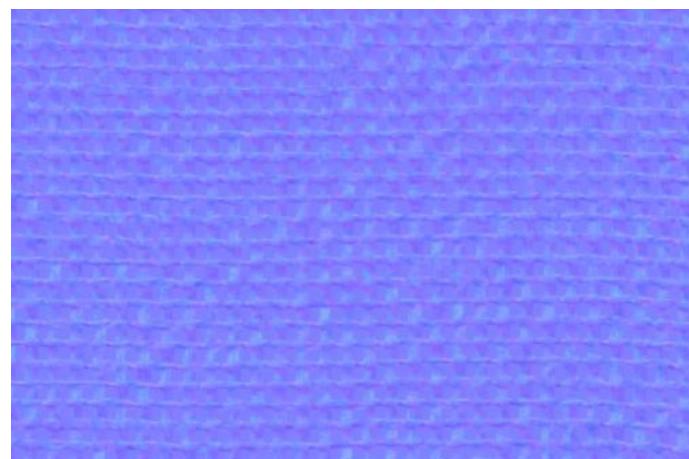
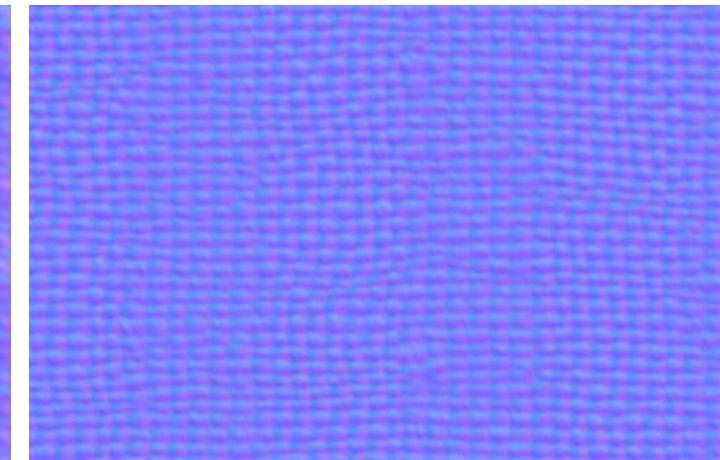
Input Image



Ground Truth



Estimation



Conclusions

Generative model tailored for high resolution material digitization

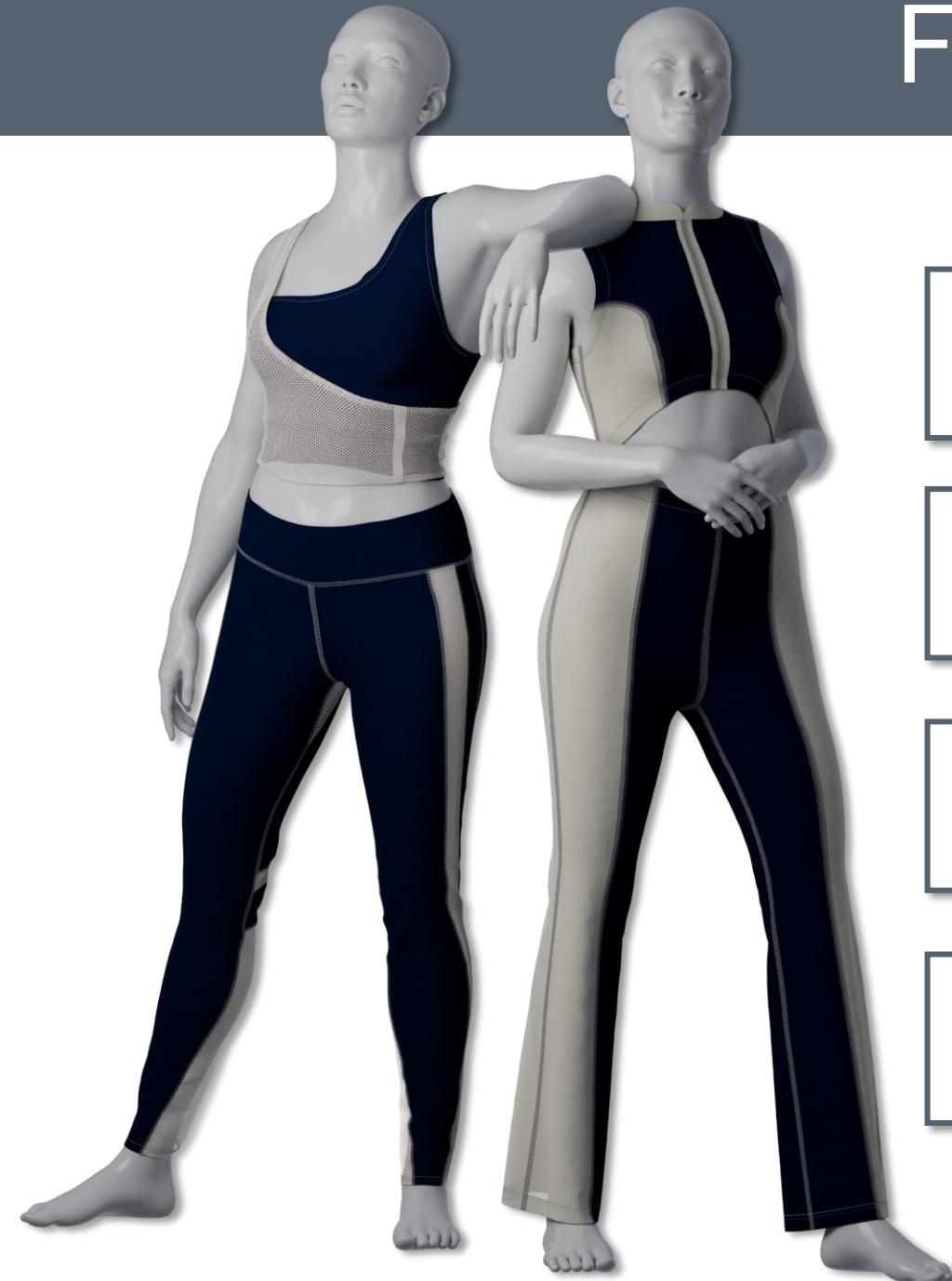
Flatbed scanners provide very high resolution inputs

Microgeometry is a powerful cue for reflectance estimation

First uncertainty quantification method for SVBRDF estimation, increasing robustness and data efficiency



Future Work



Estimate albedos

Expand material model: Transmittance, anisotropy

Increase dataset size and variety

Allow for other scanning devices



Thank you!

Additional Information

<https://carlosrodriguezpardo.es/projects/UMat/>



UMat: Uncertainty-Aware Single Image High Resolution Material Capture

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Rey Juan Carlos